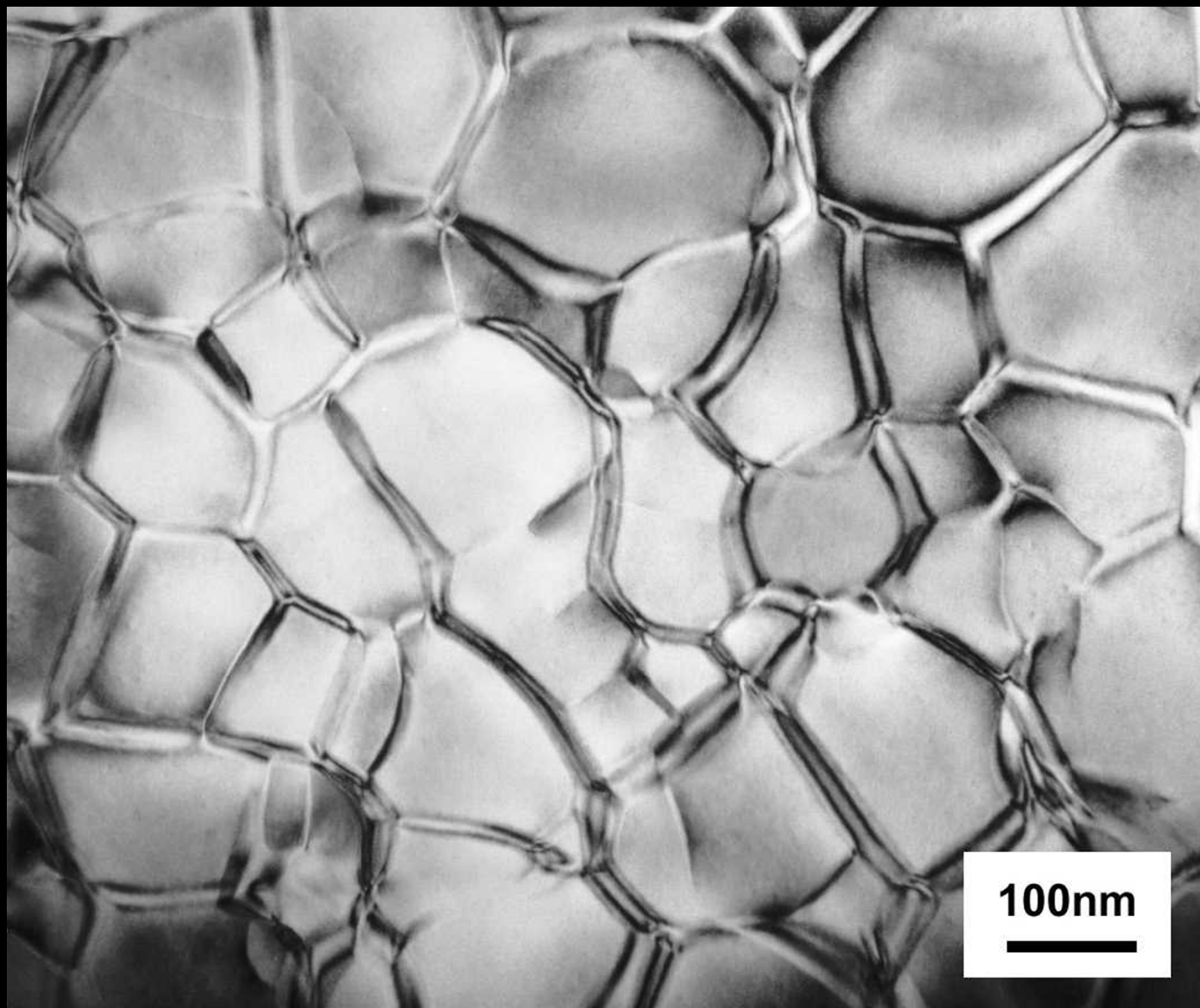


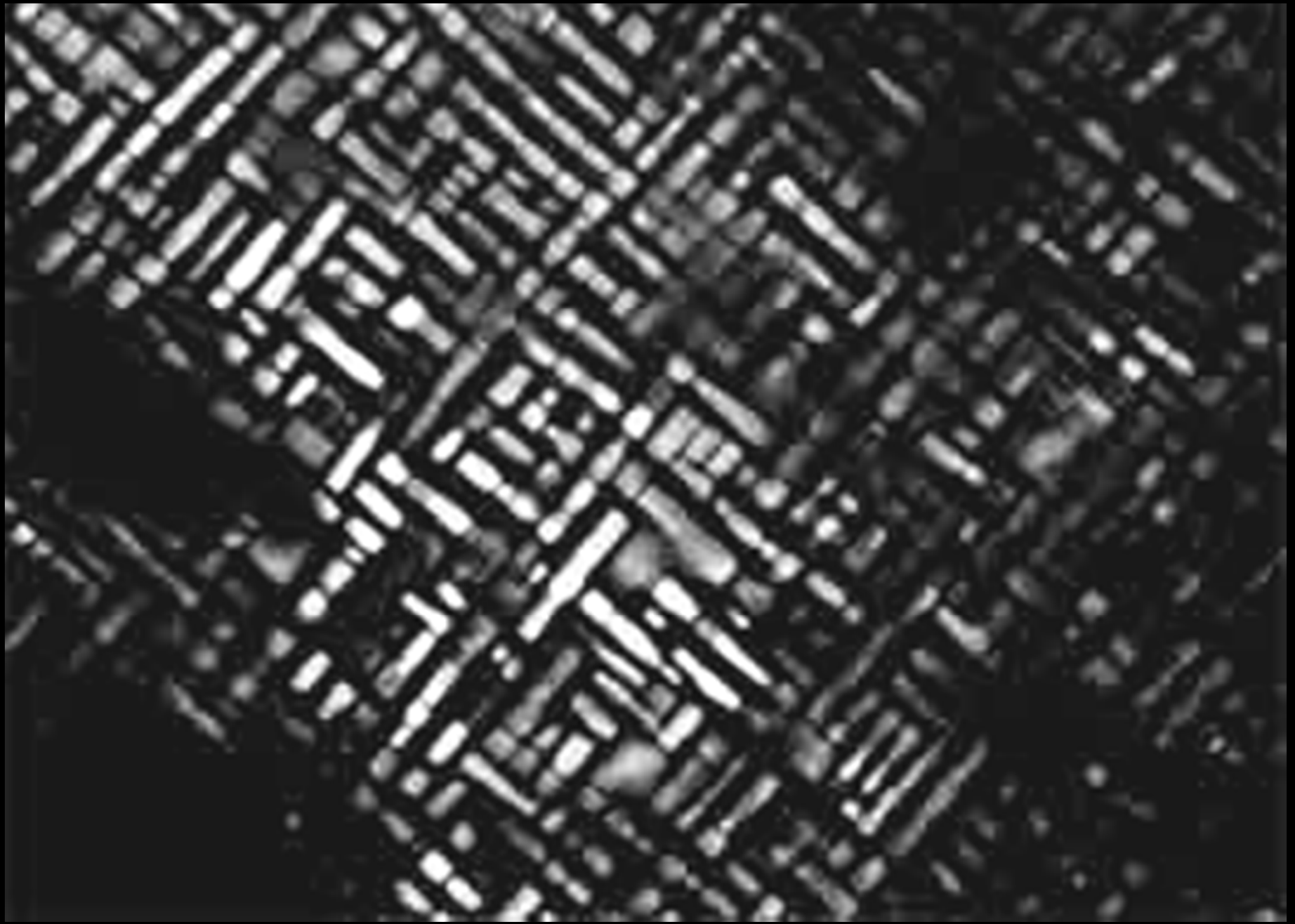
400 nm

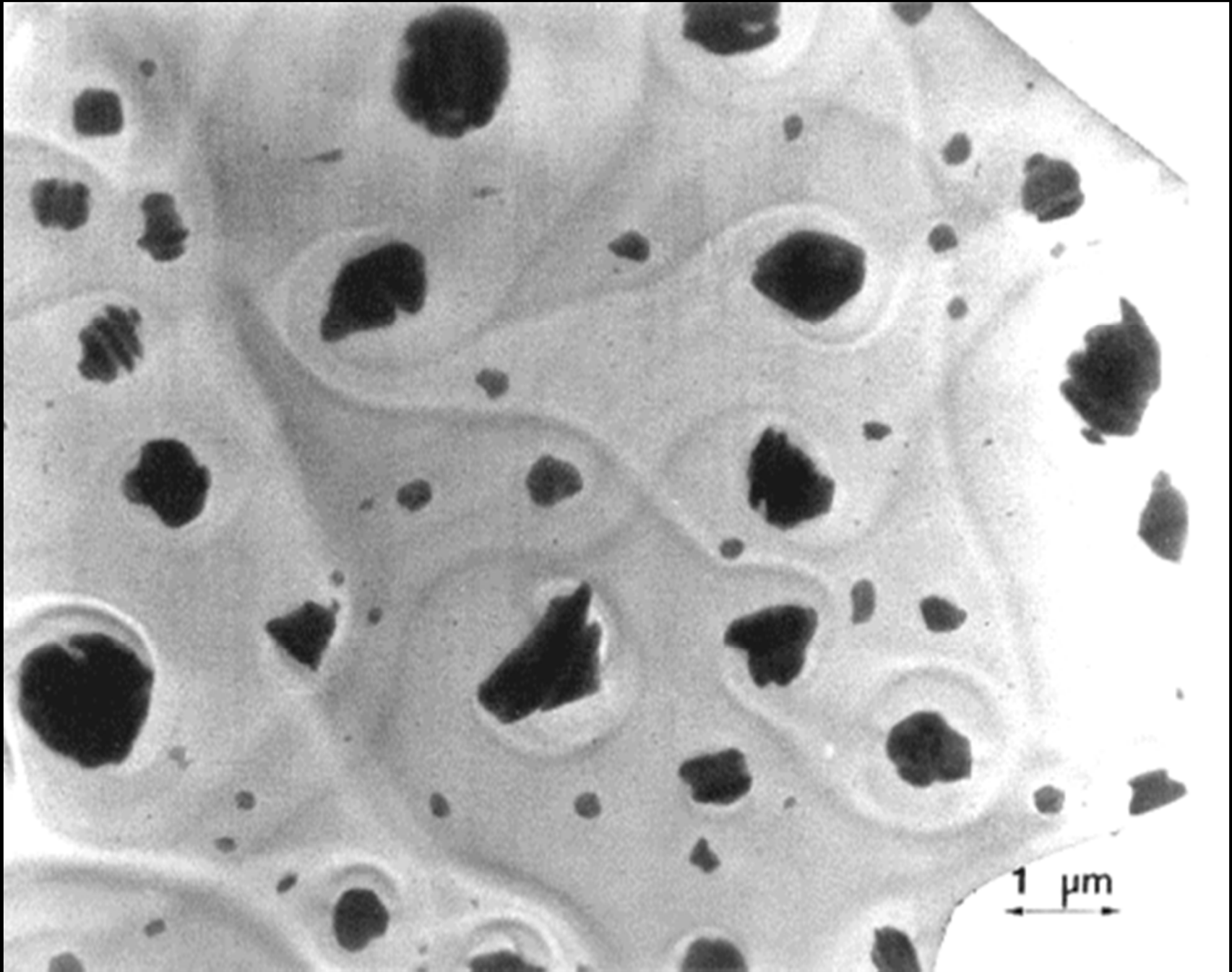


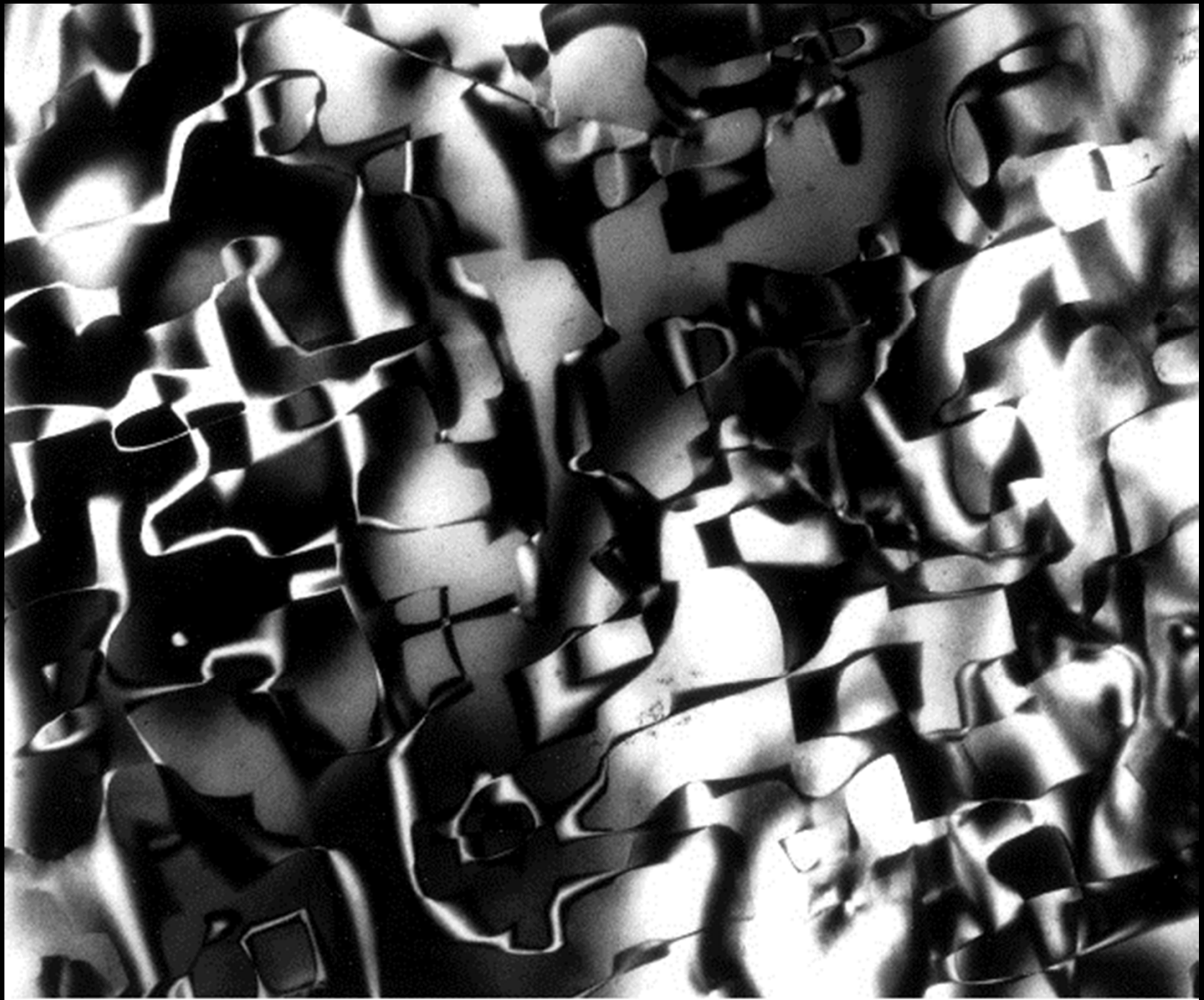


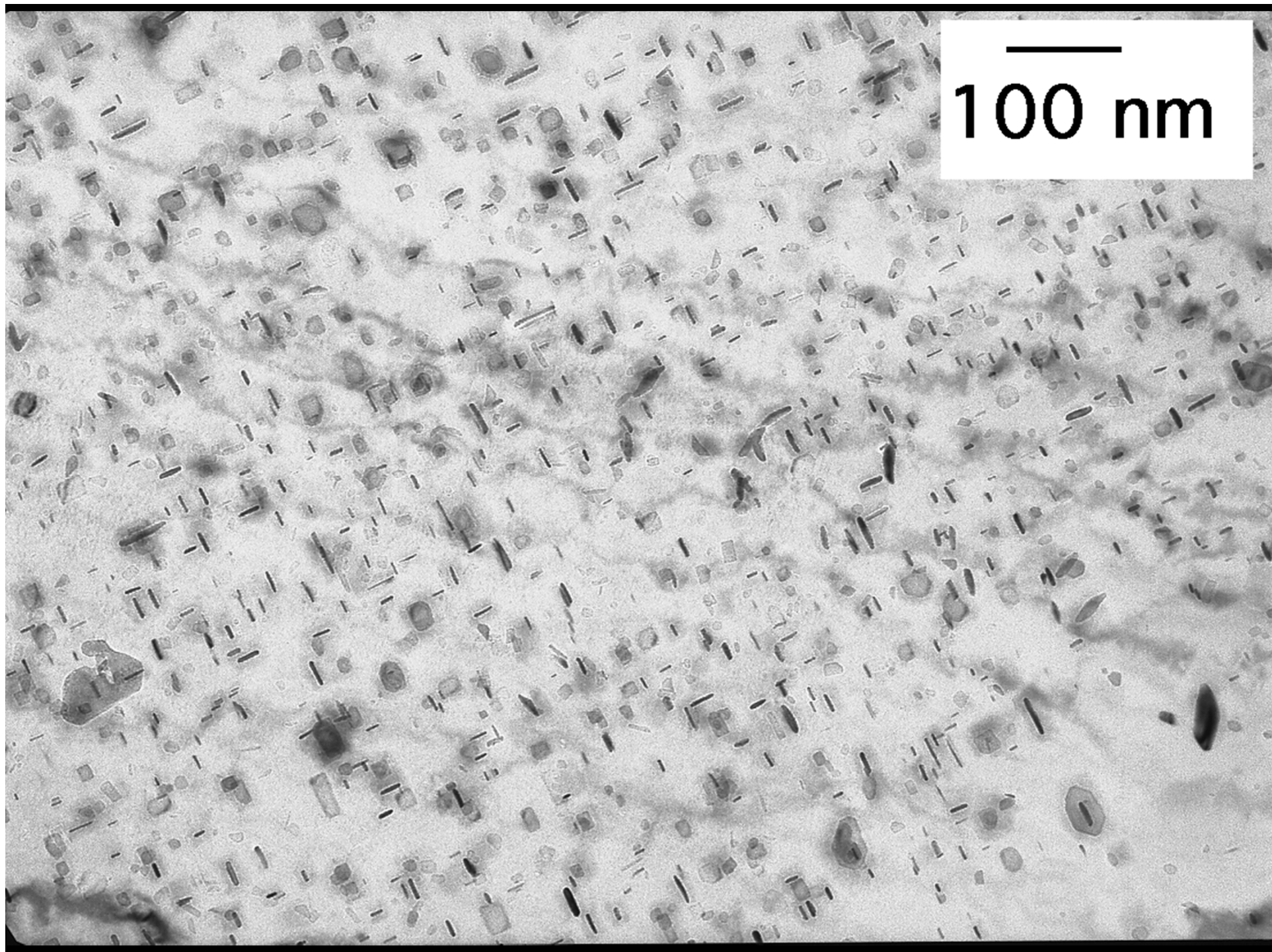
100nm

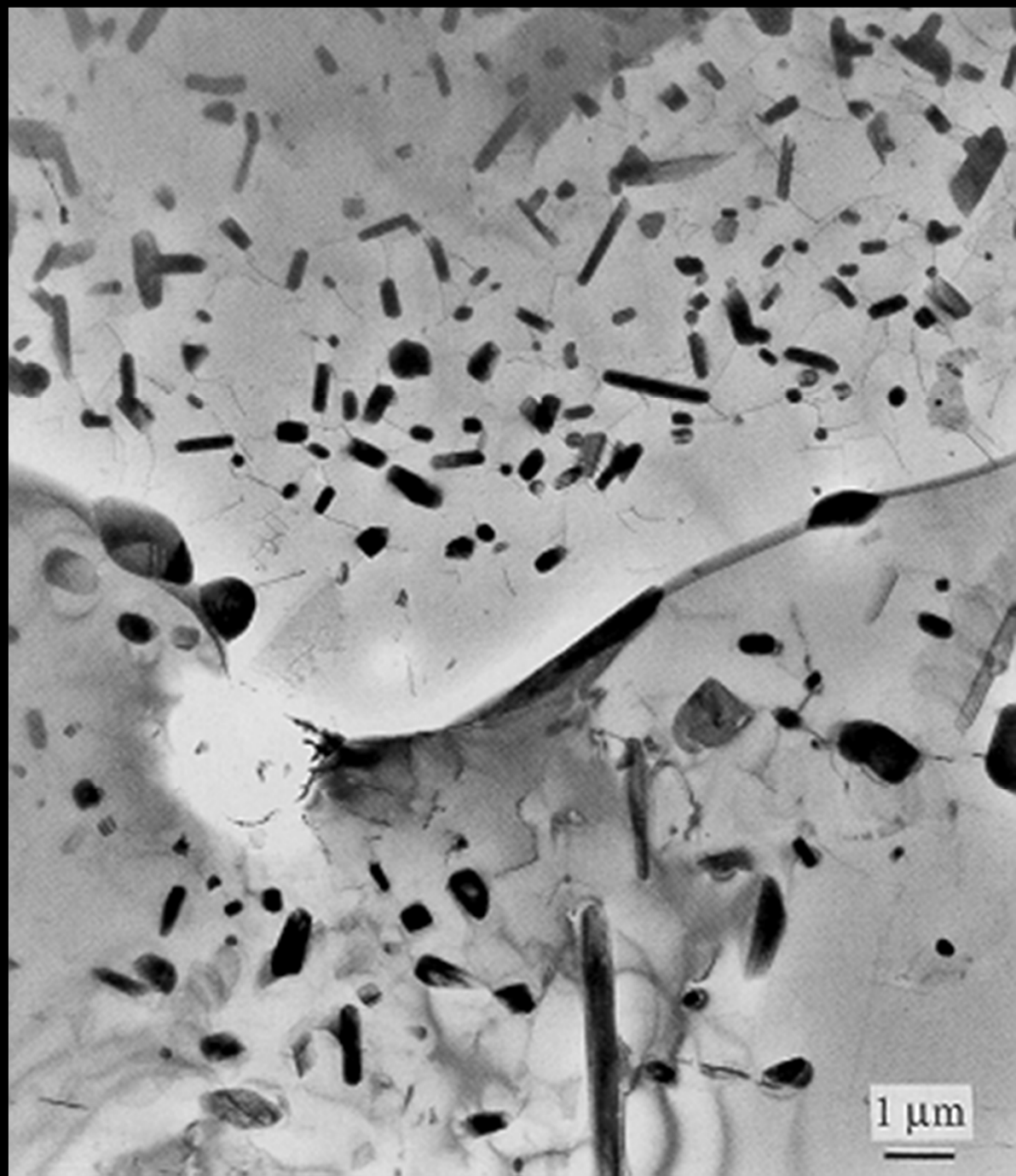


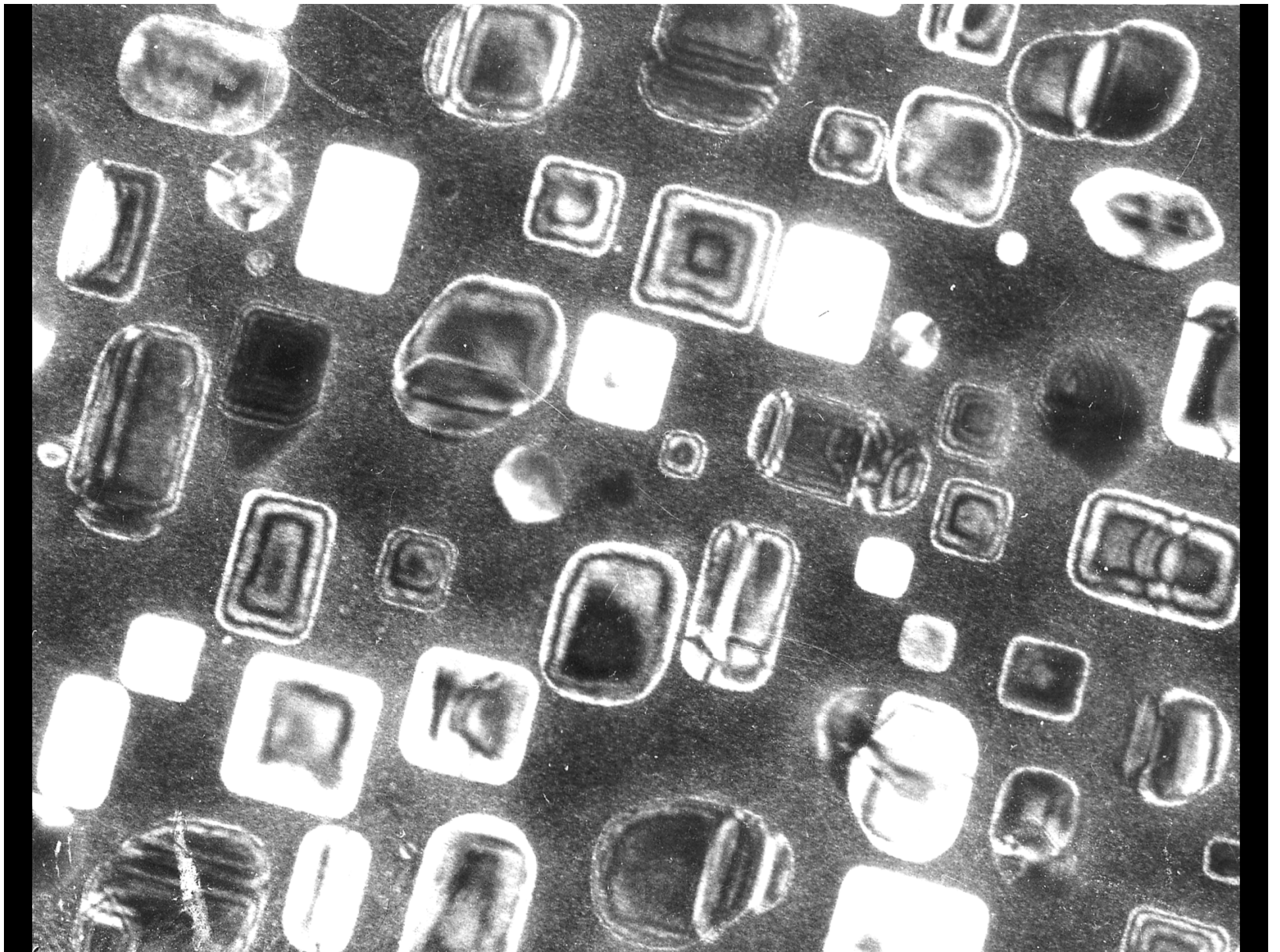


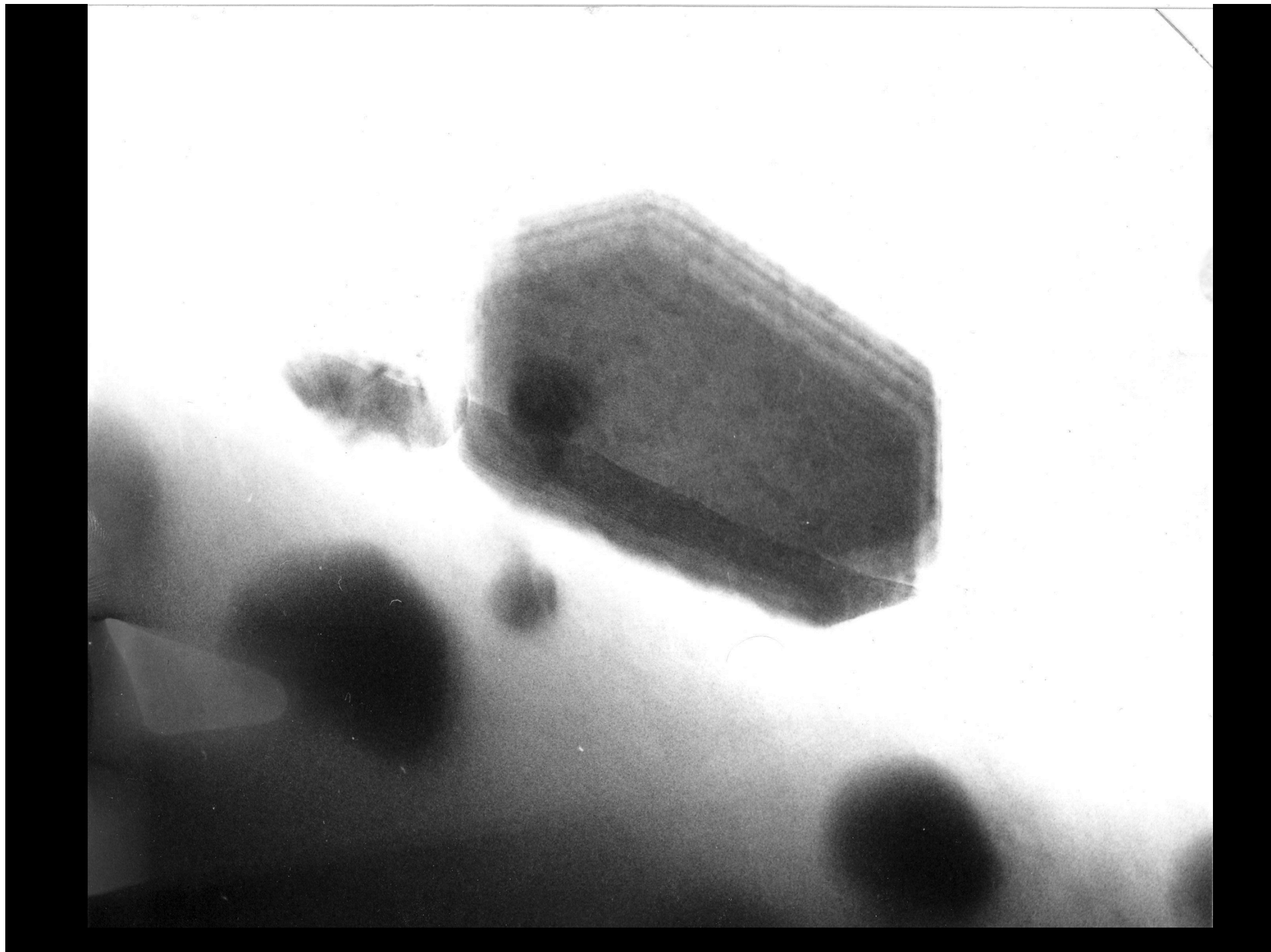




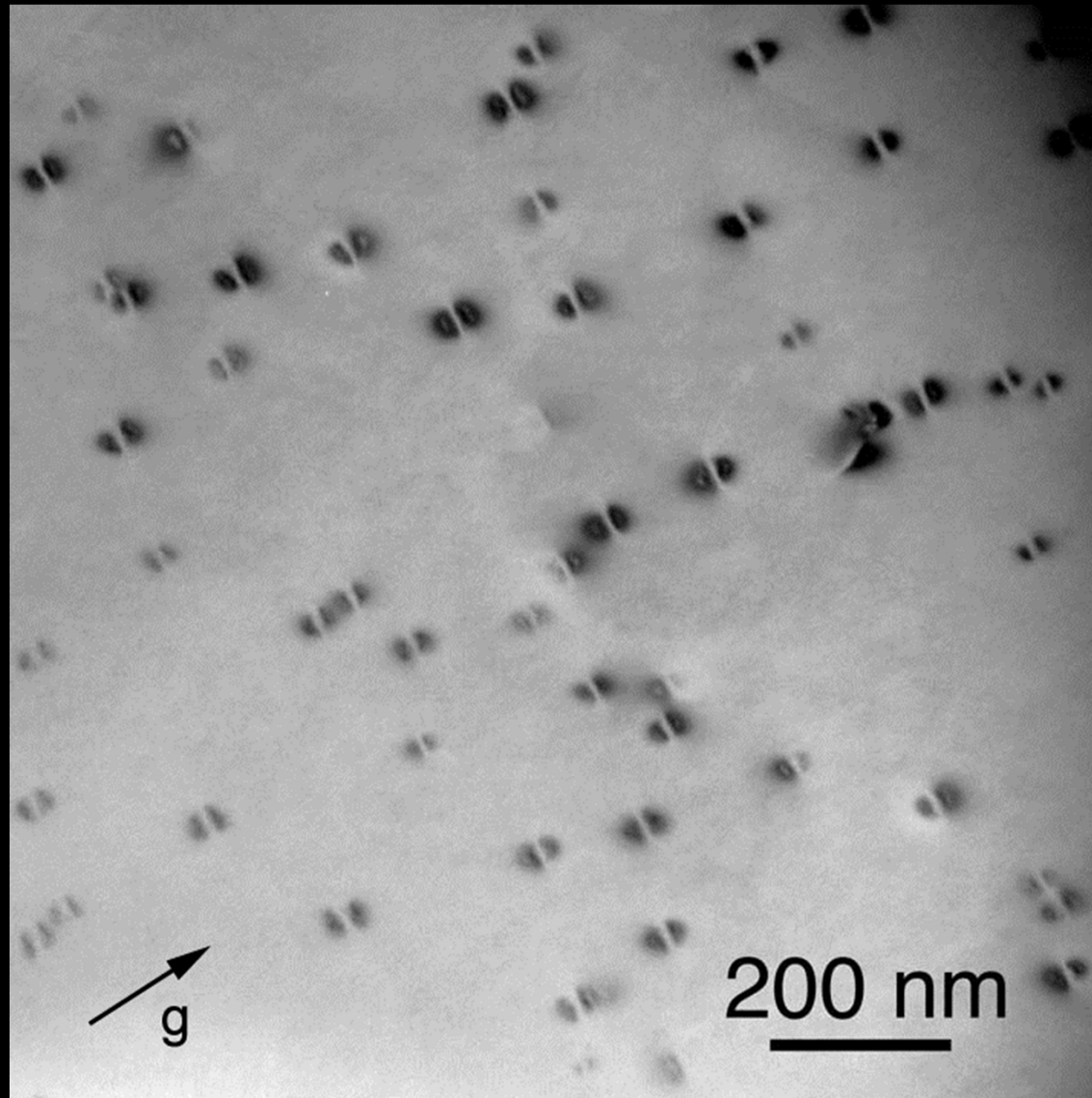




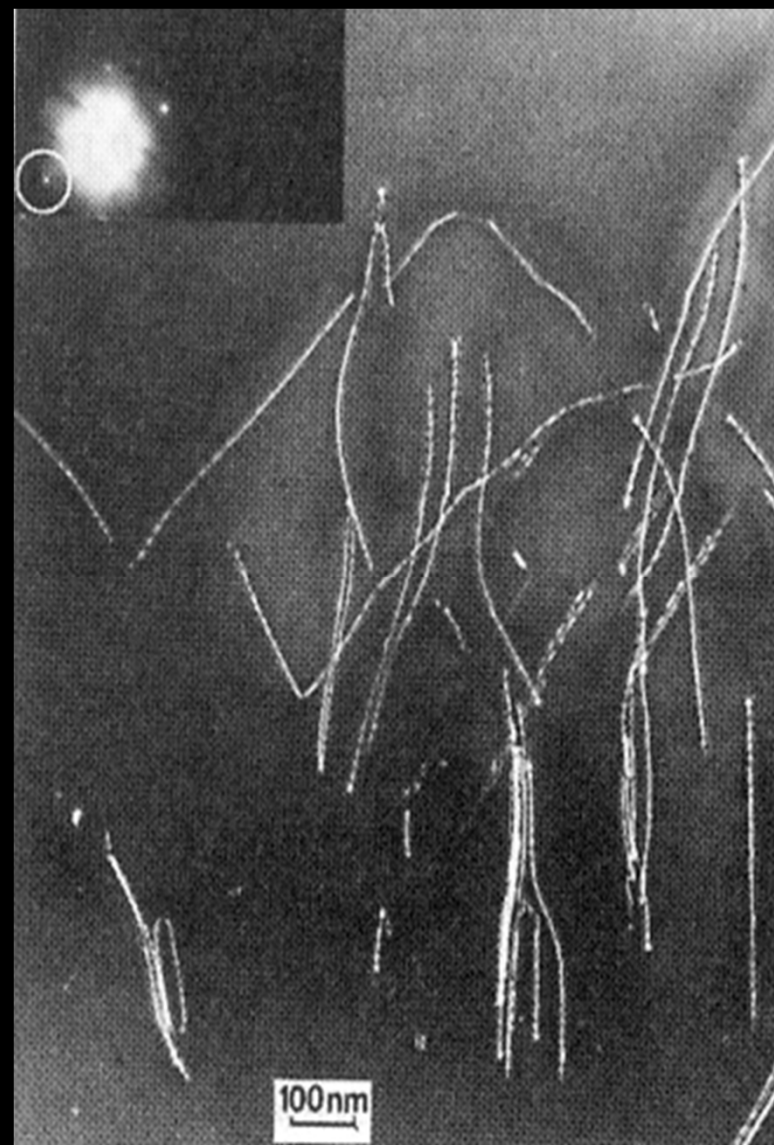
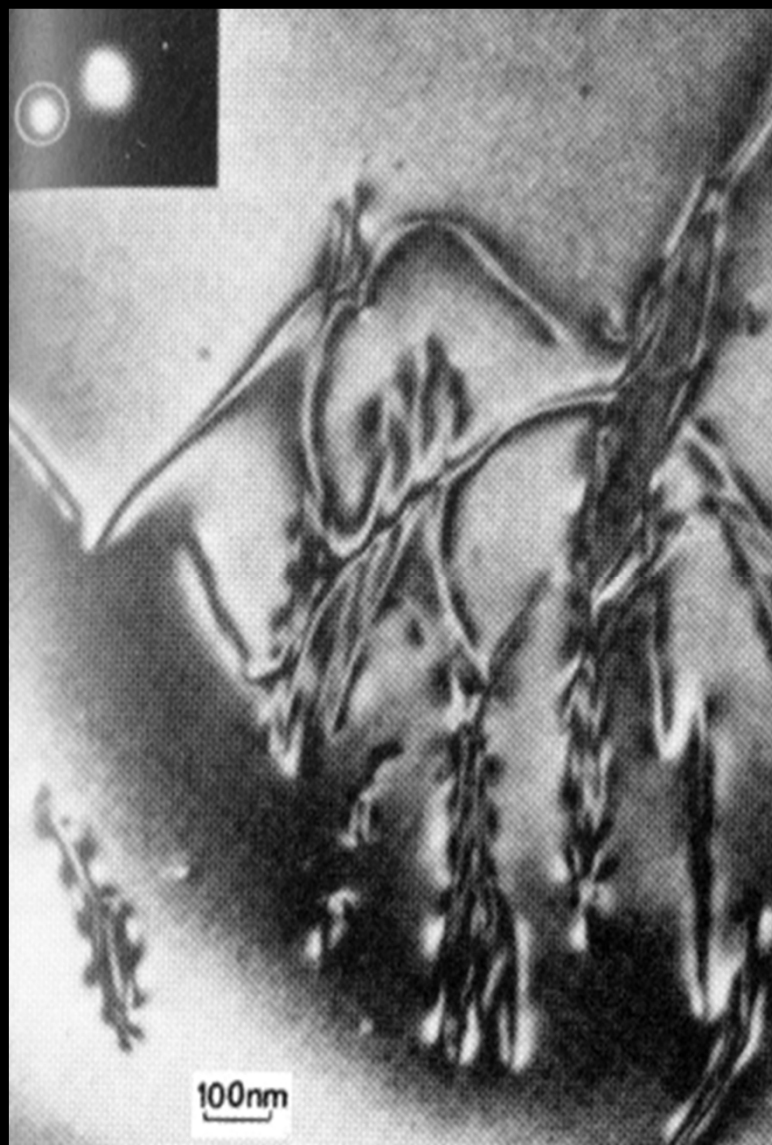


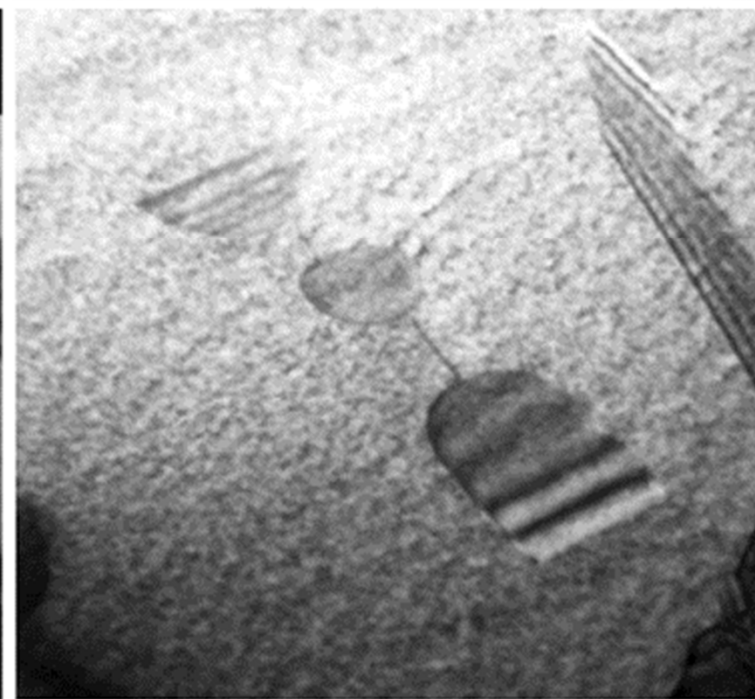
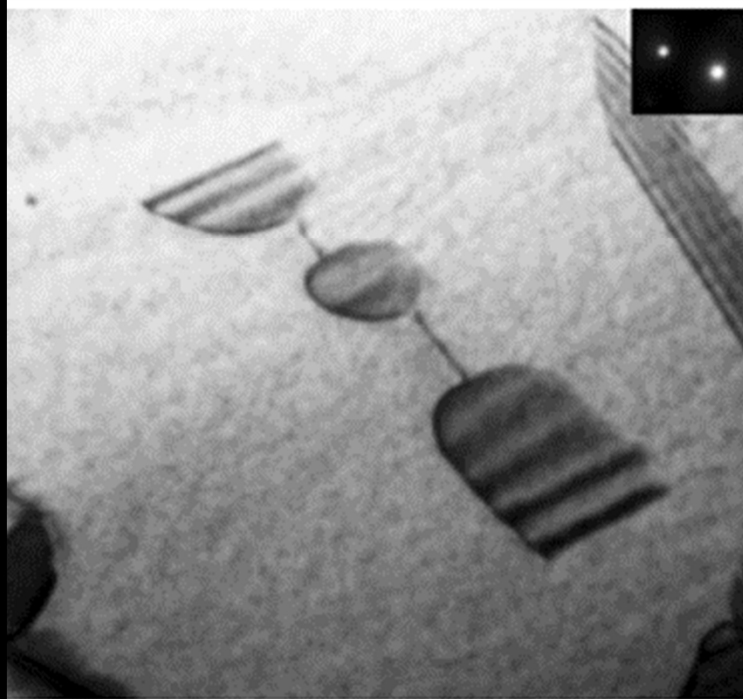
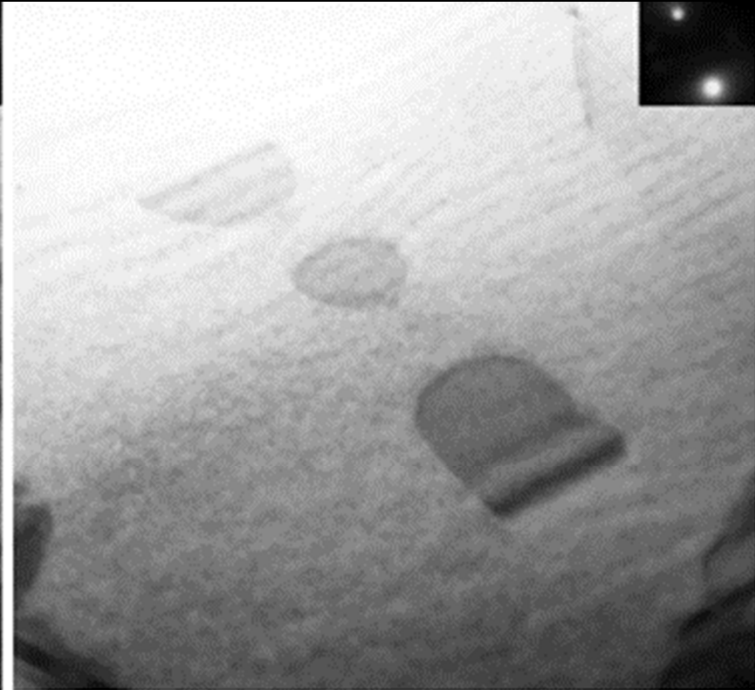
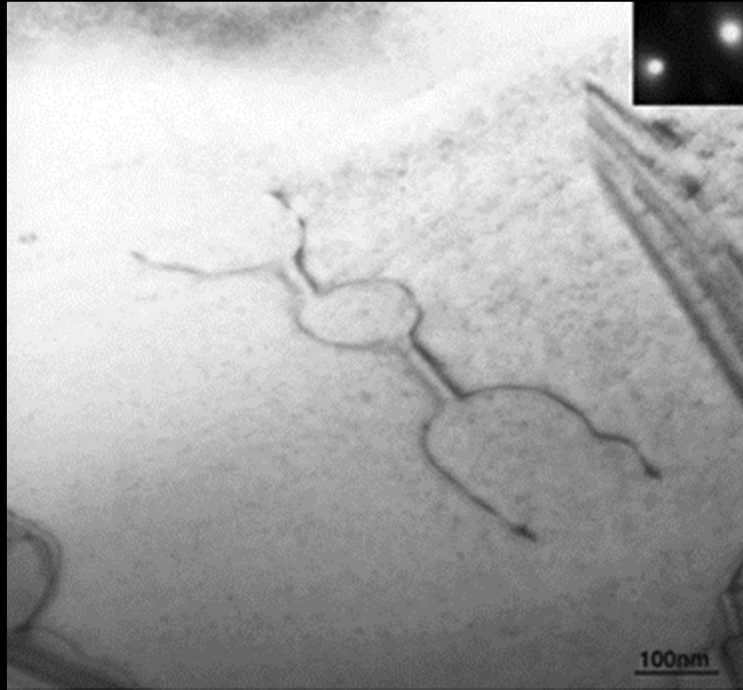


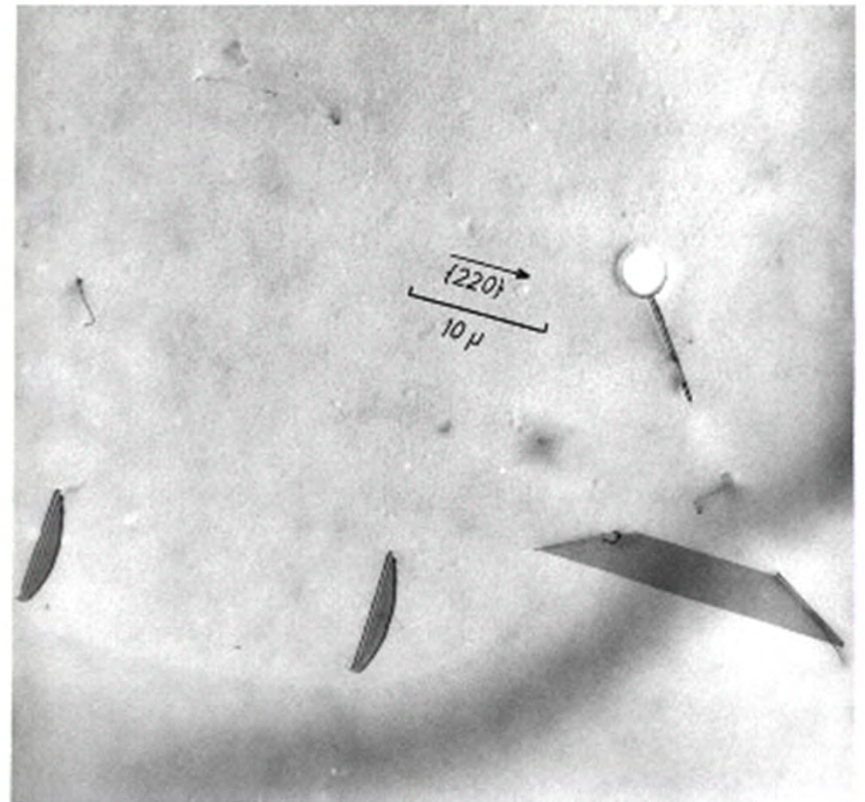
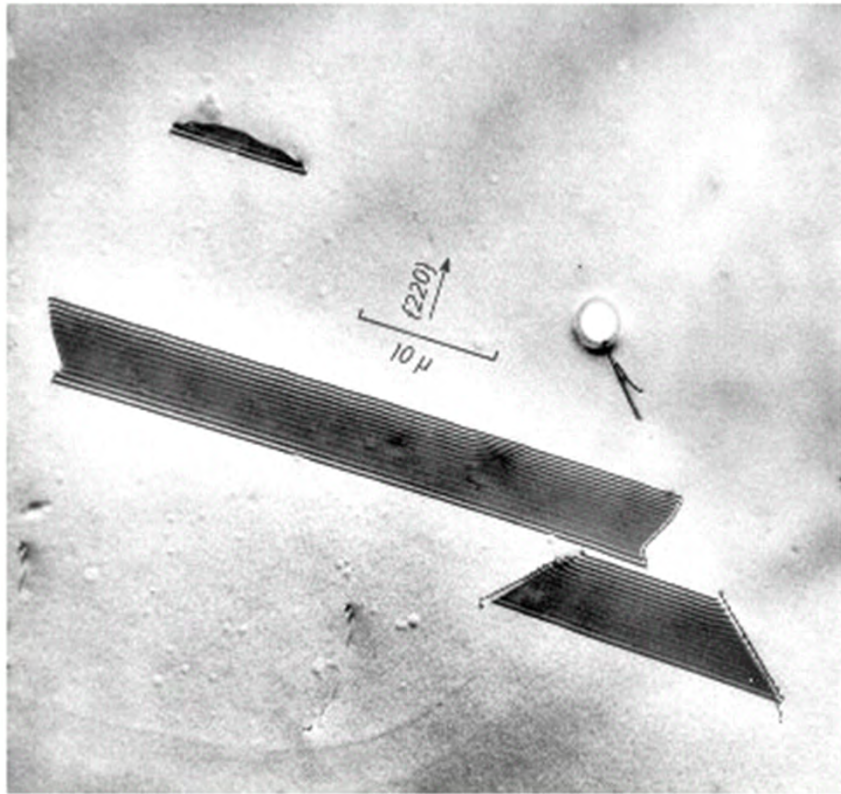
Coherency of Al_3Sc Precipitates¹

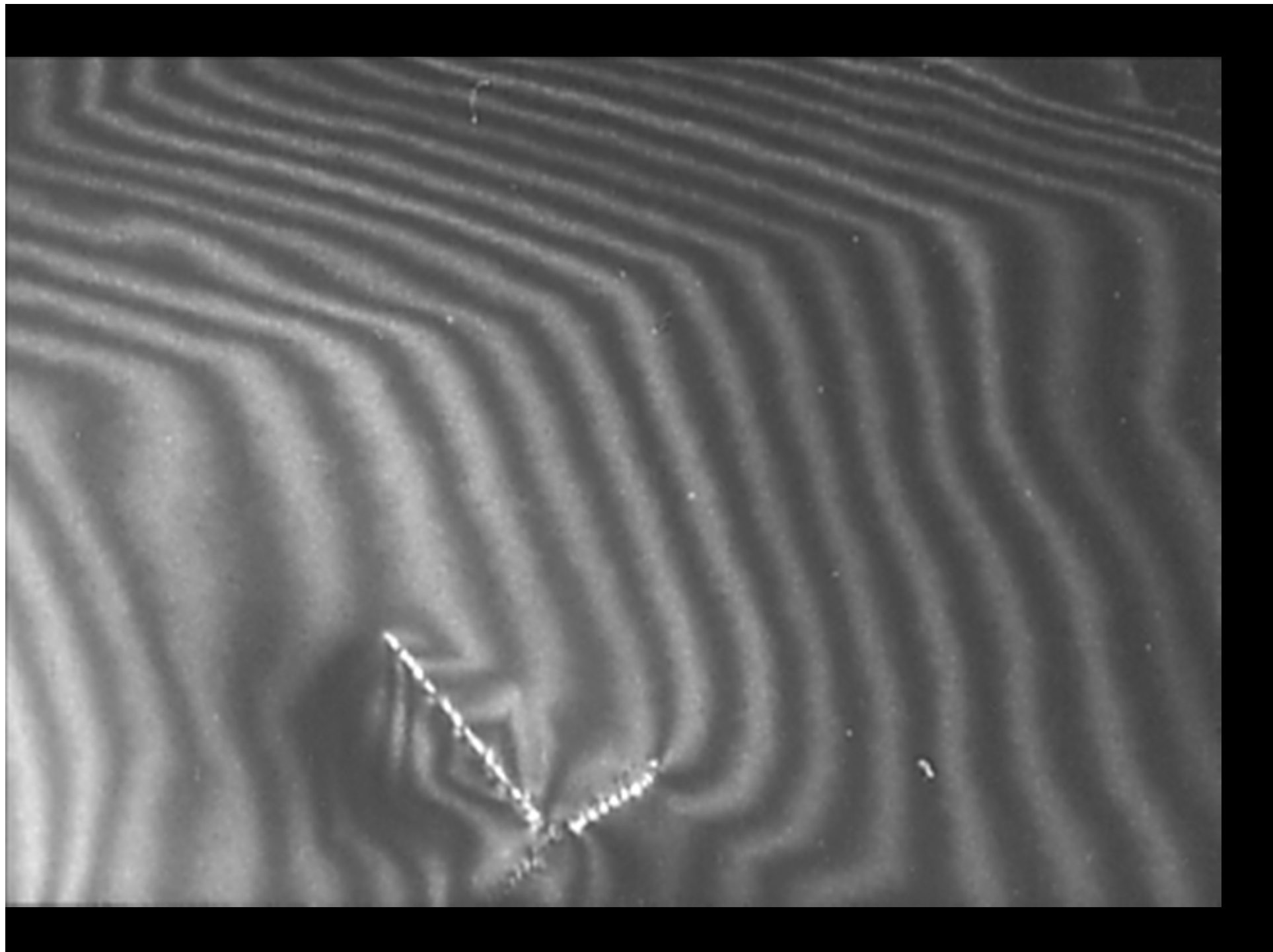


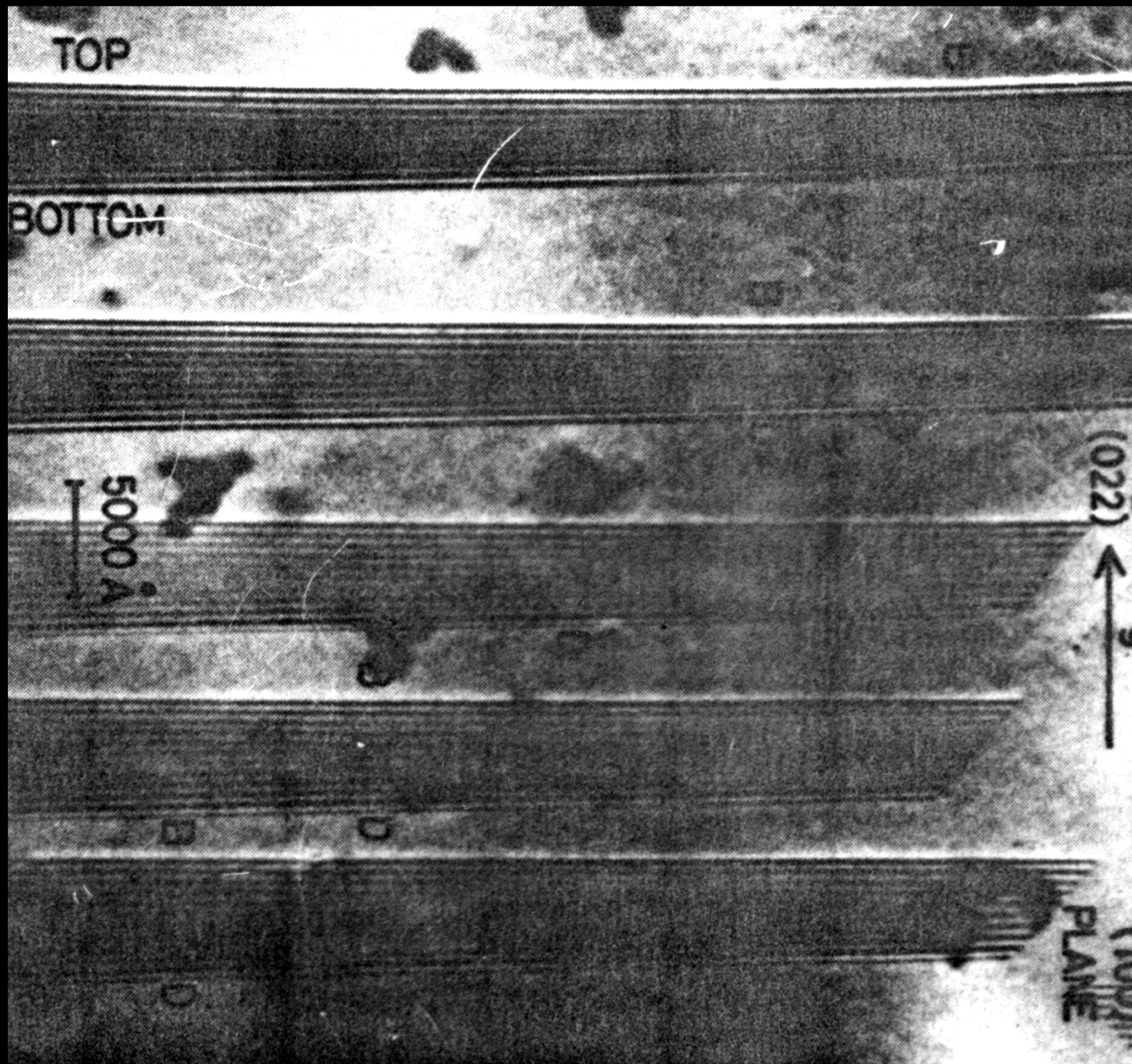
¹E.A. Marquis, D.N. Seidman, *Acta Mater.* **49** (2001) 1909-1919.

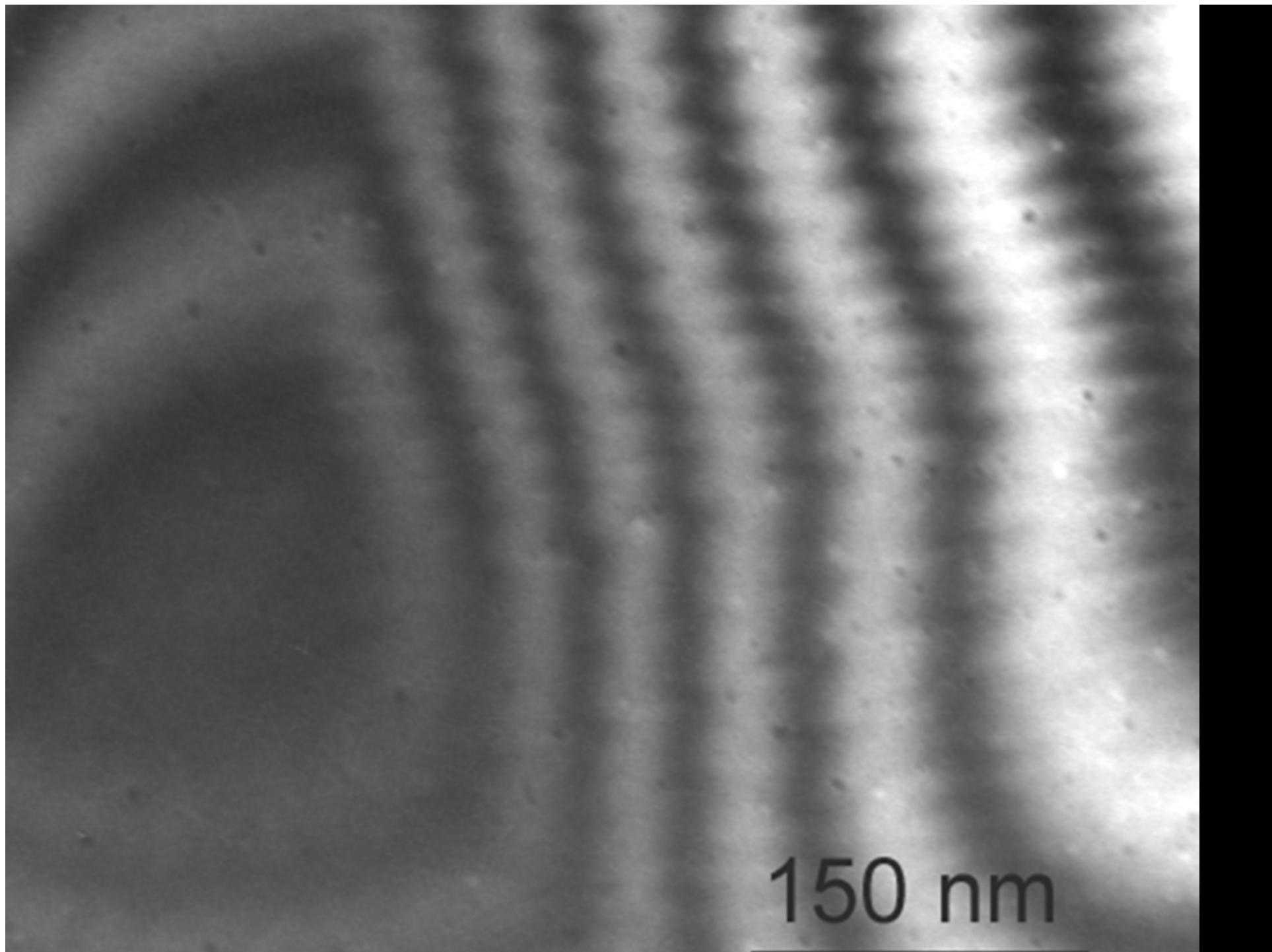


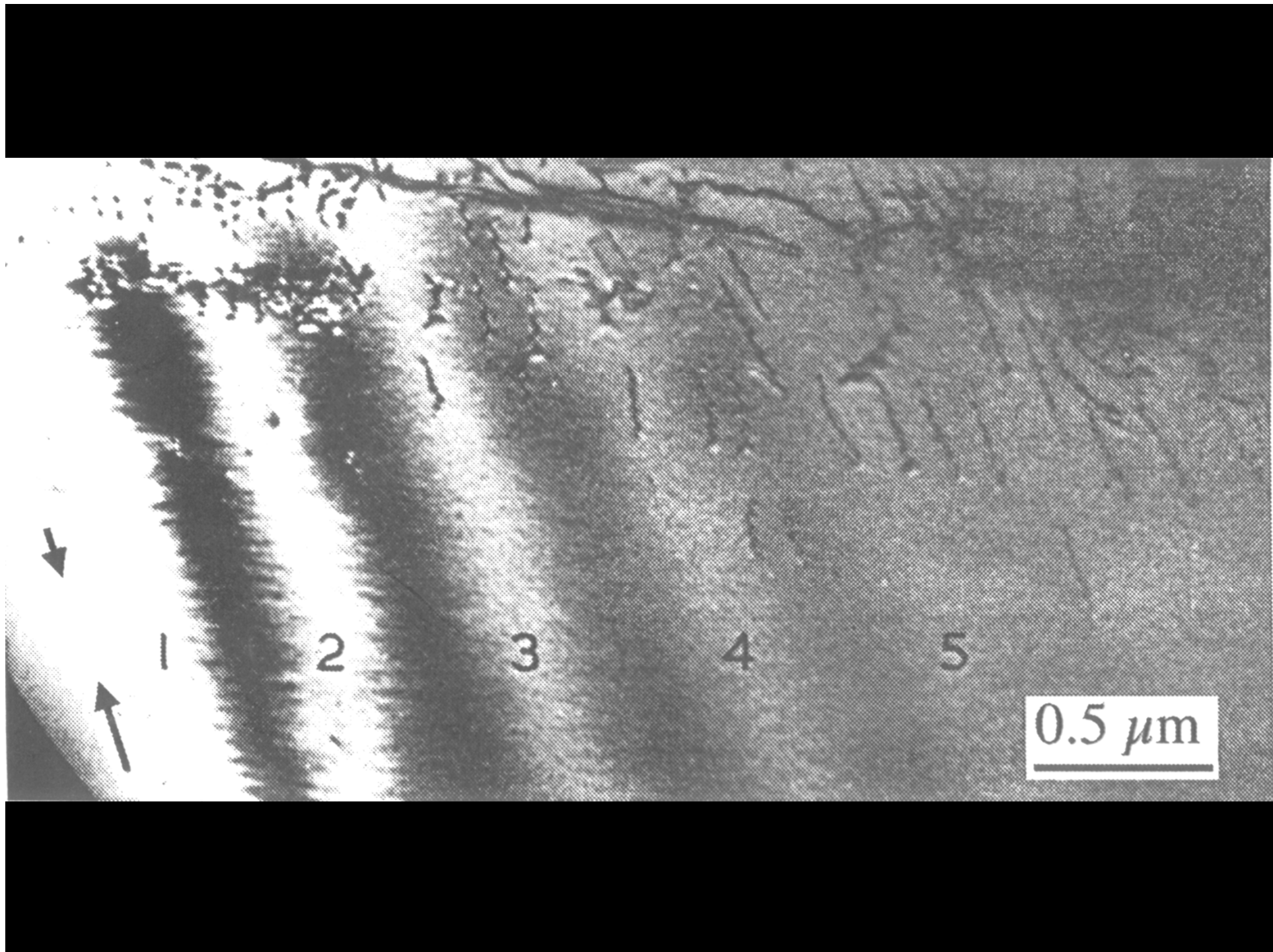




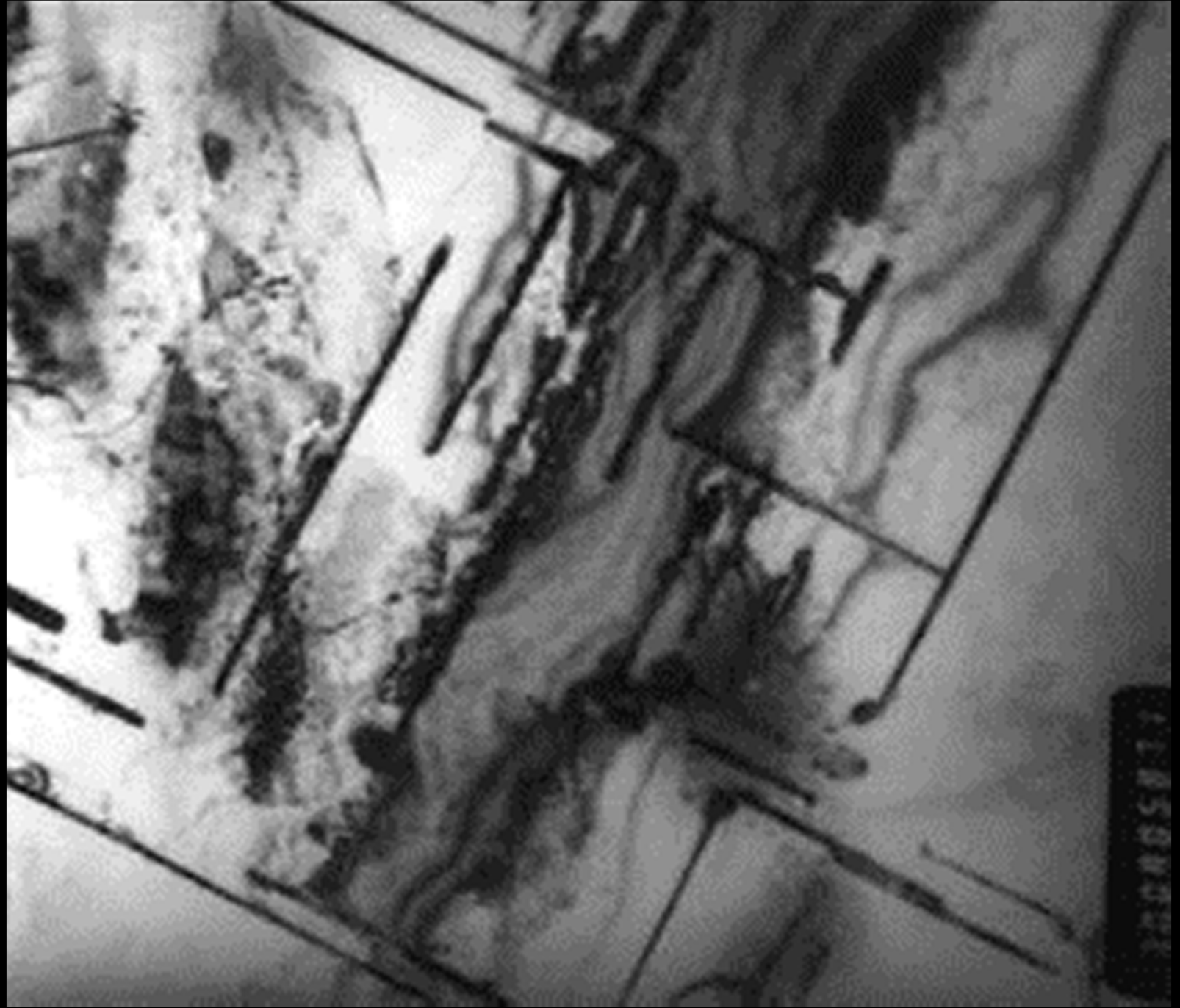


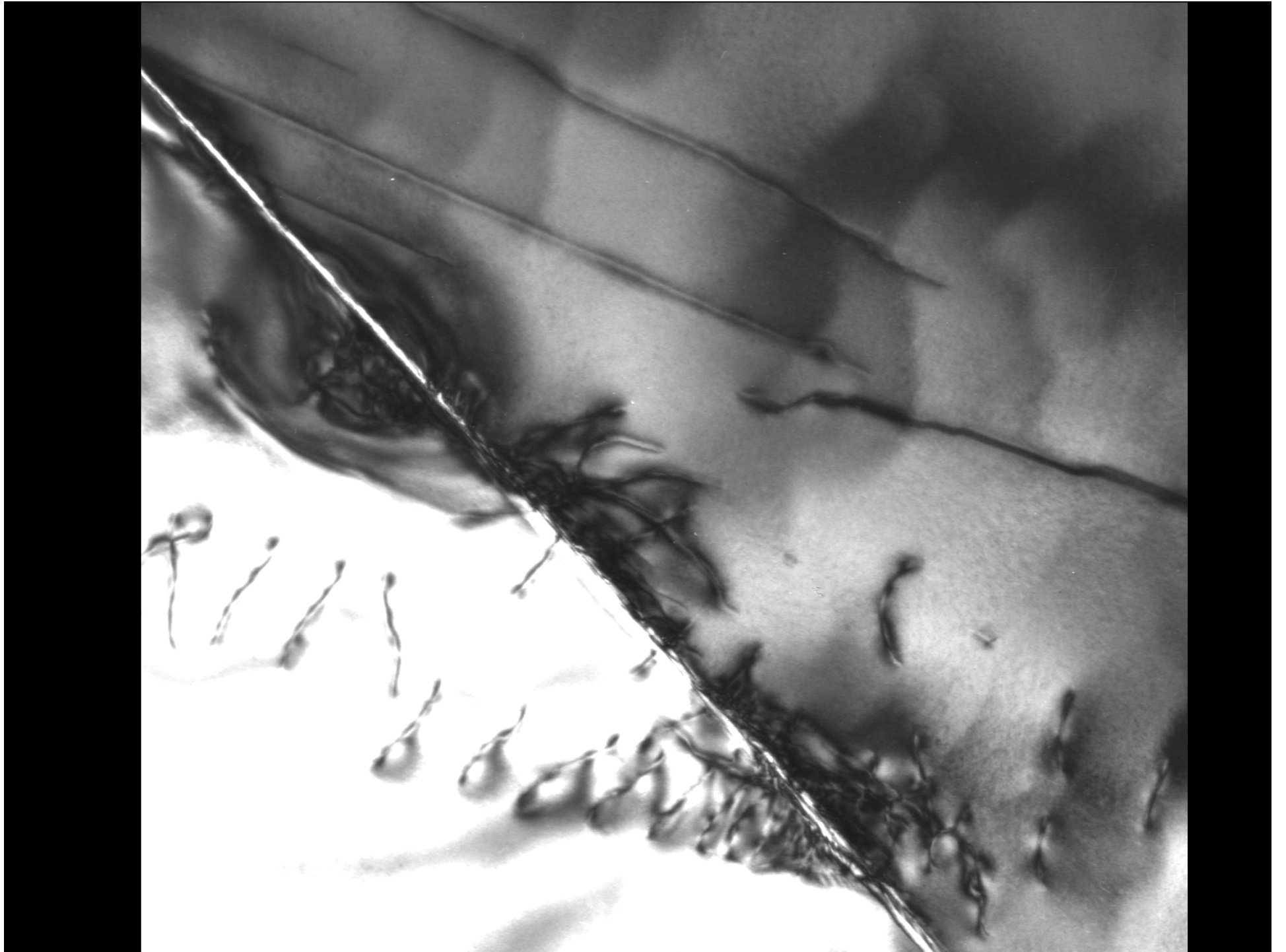


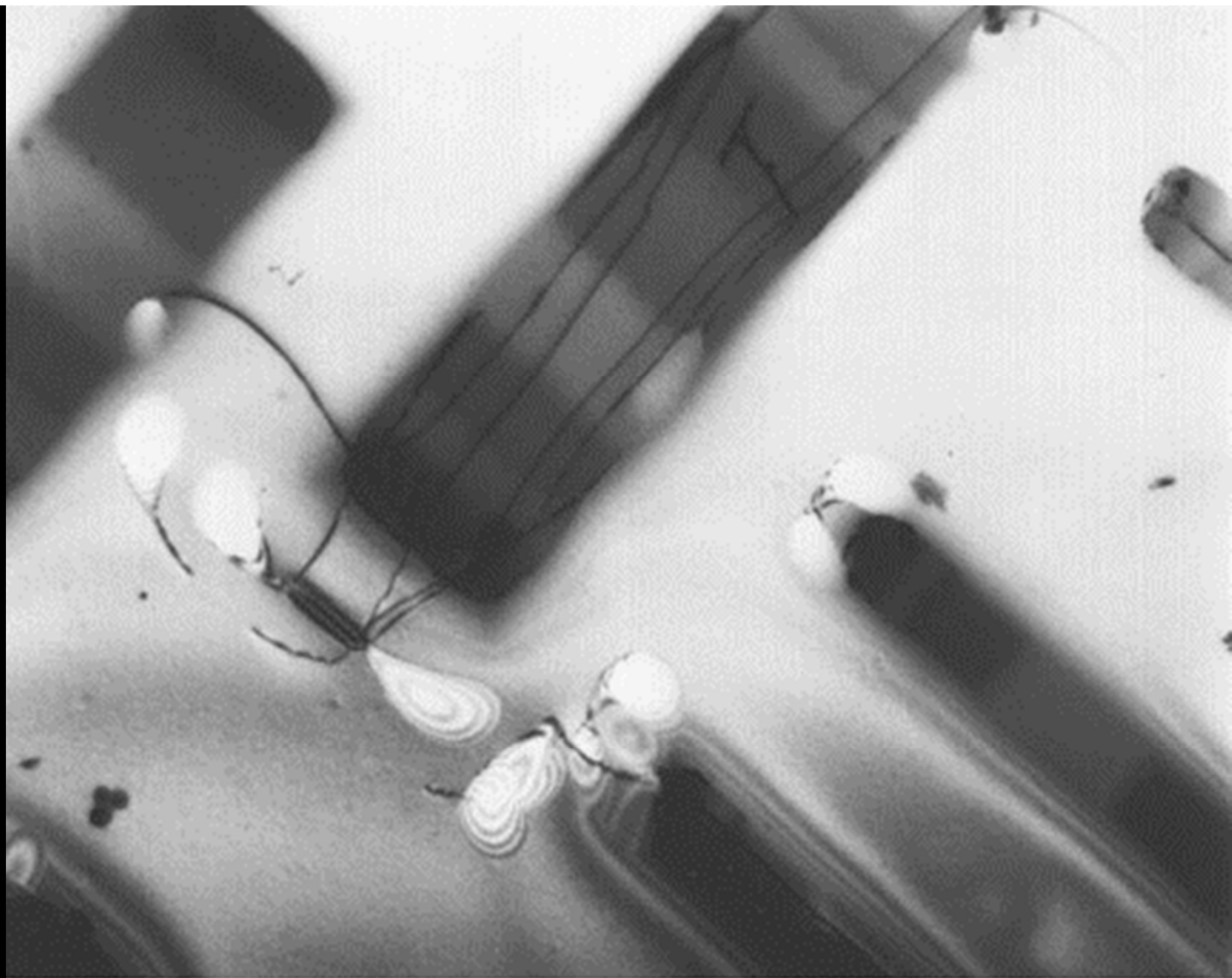












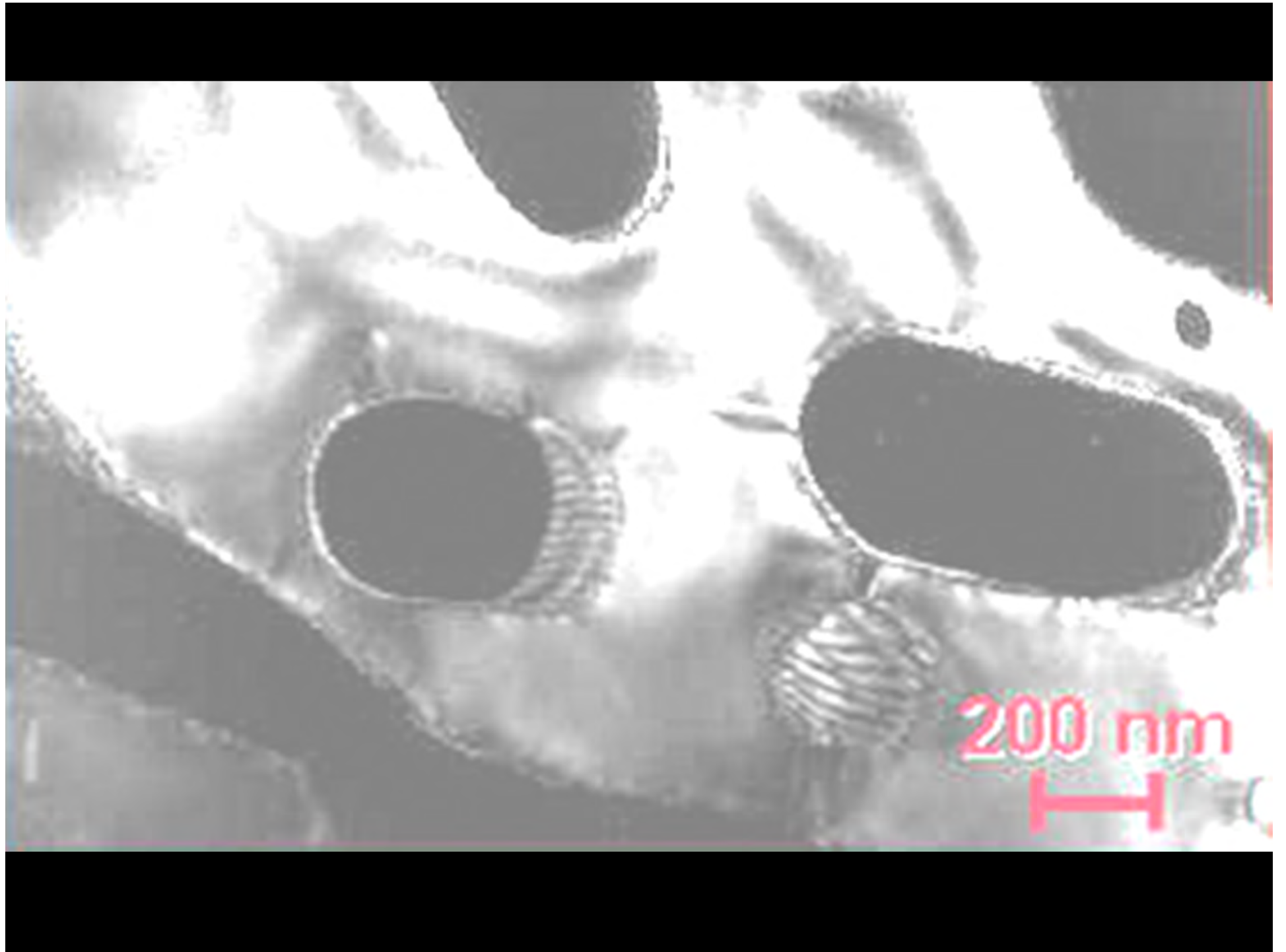
High voltage micrograph of aluminum contact lines on silicon device showing failure due to

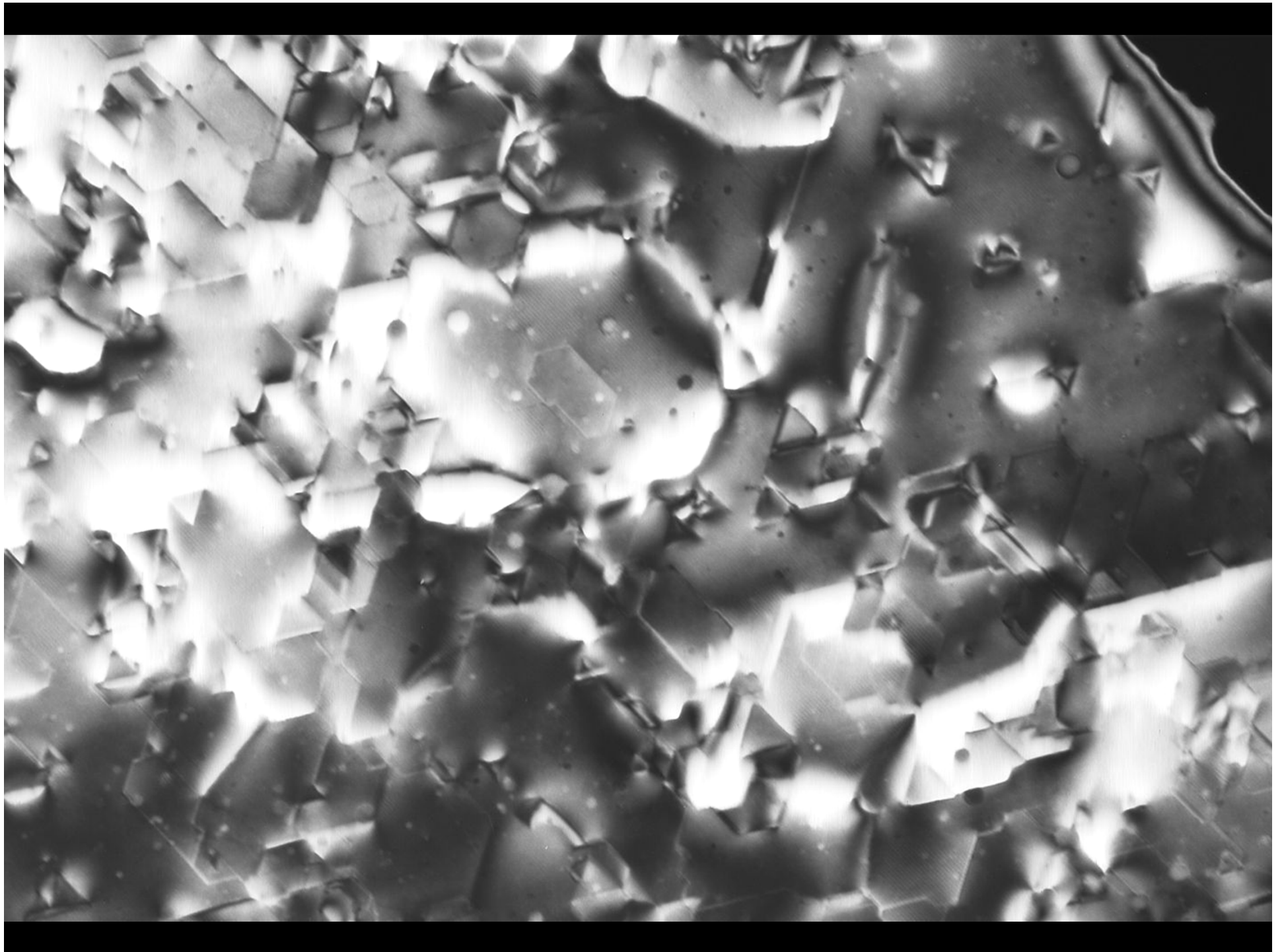
Moire Patterns (dislocations) See Wolfram Demo Page



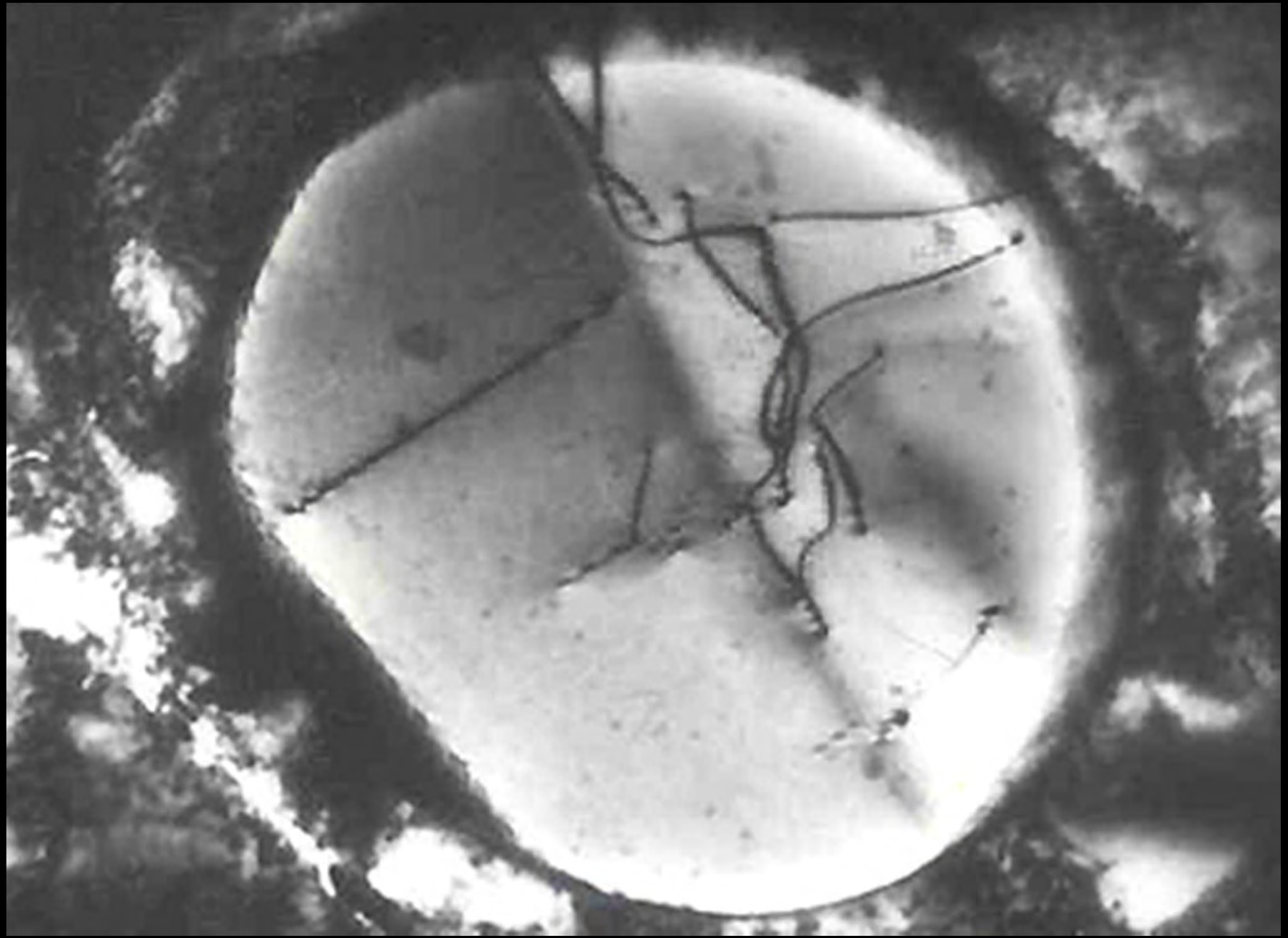
MoirePatternOfTwoStraightLinePatterns.nbp

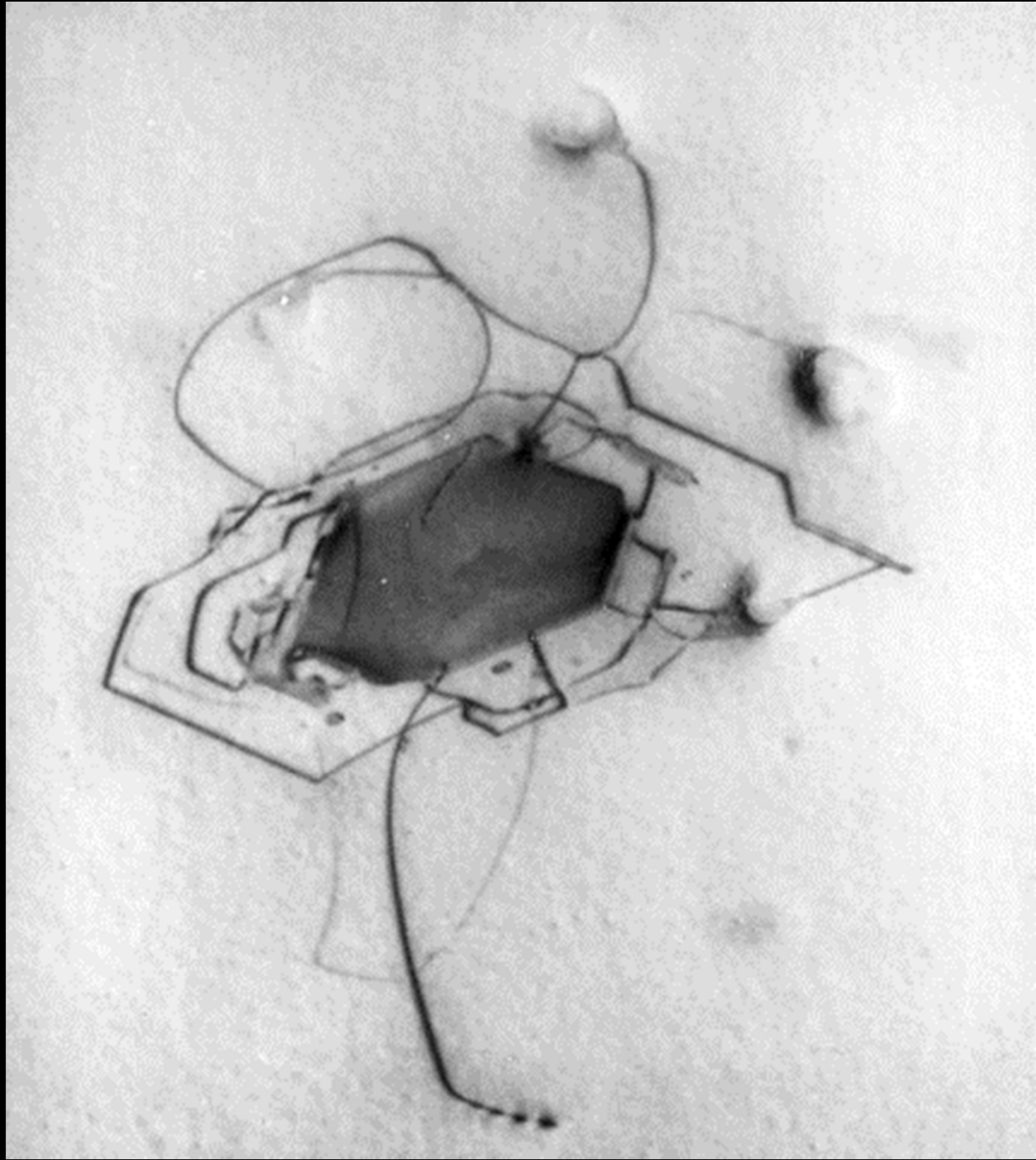
MoirePatterns.nbp

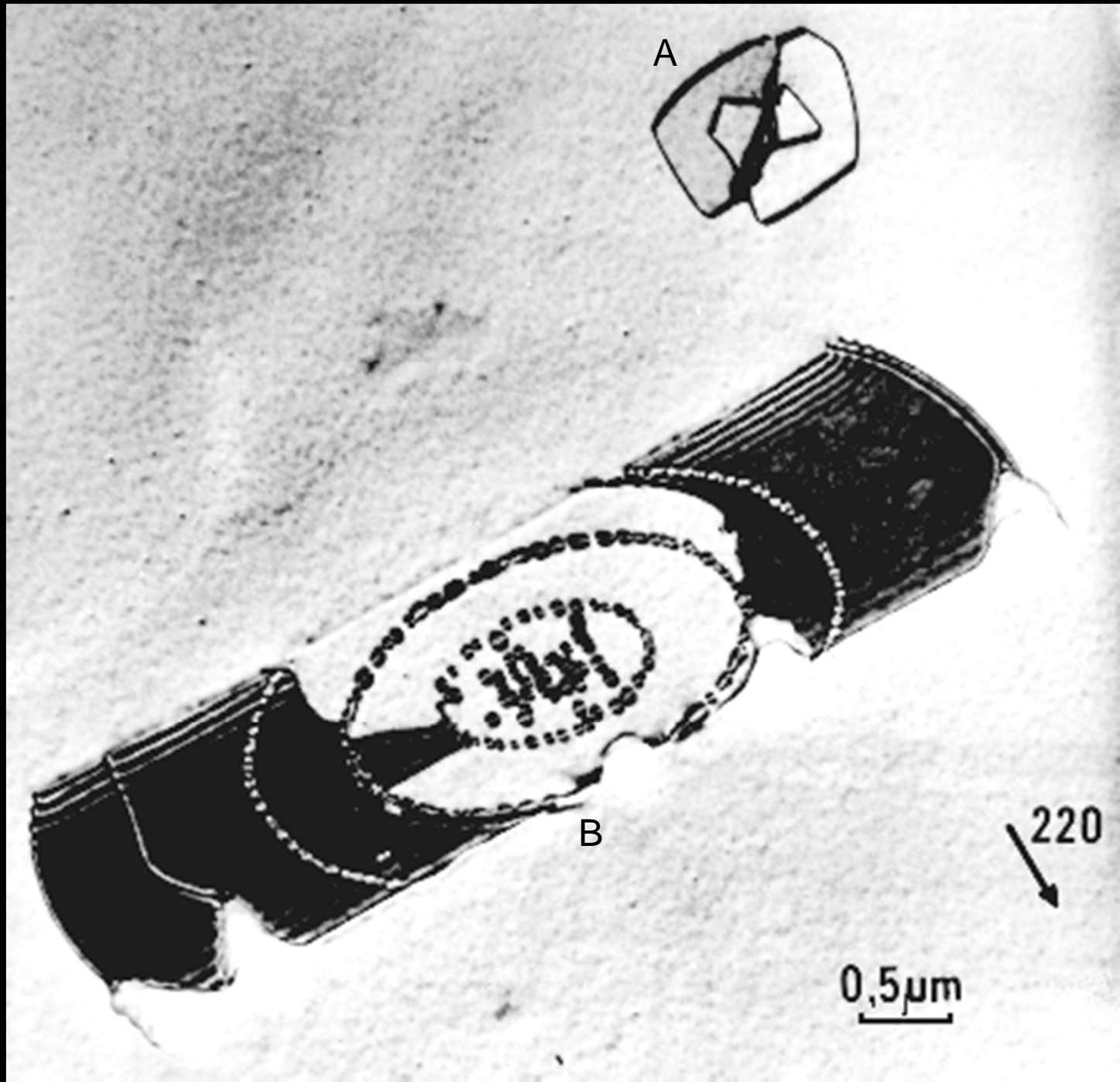


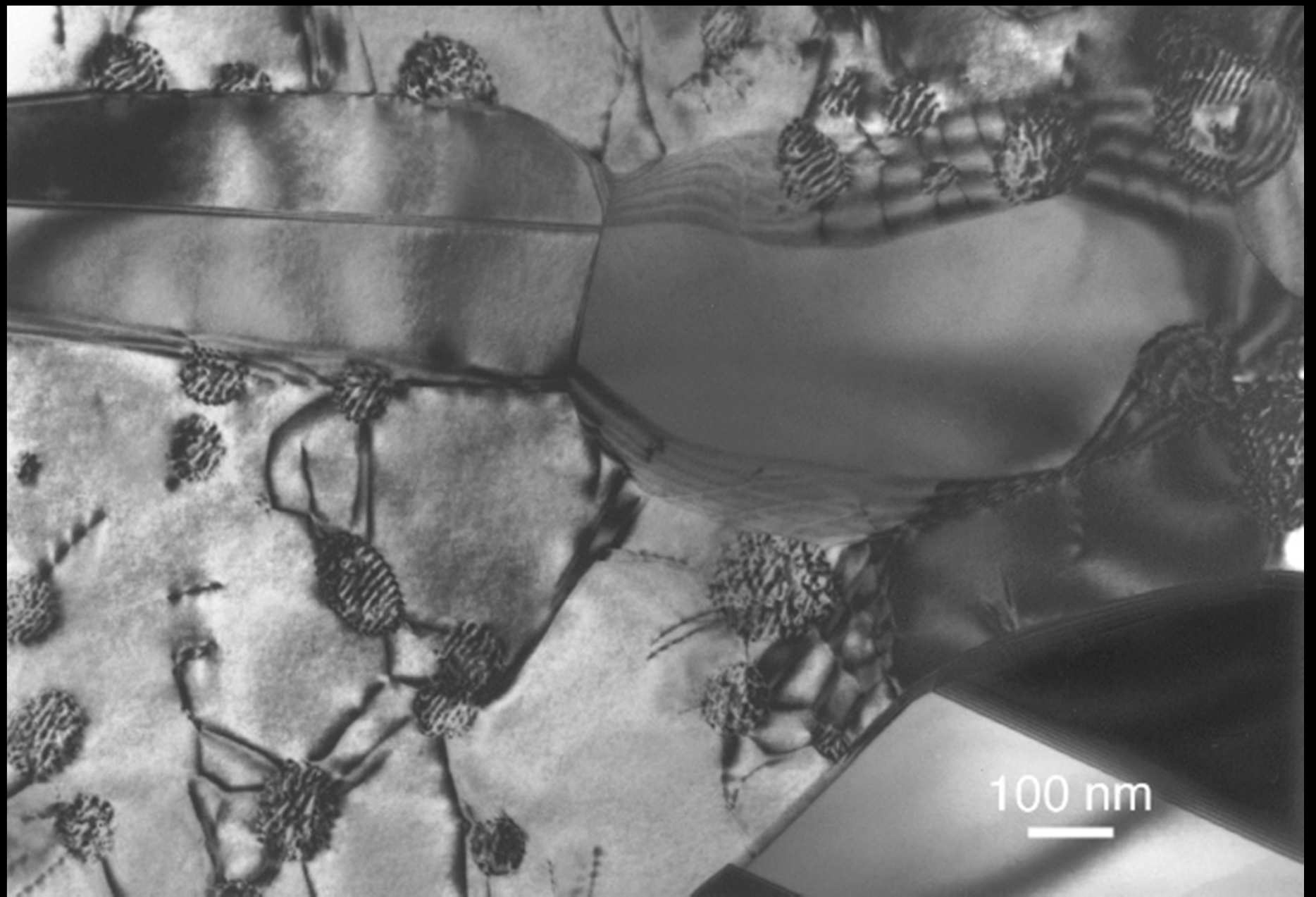


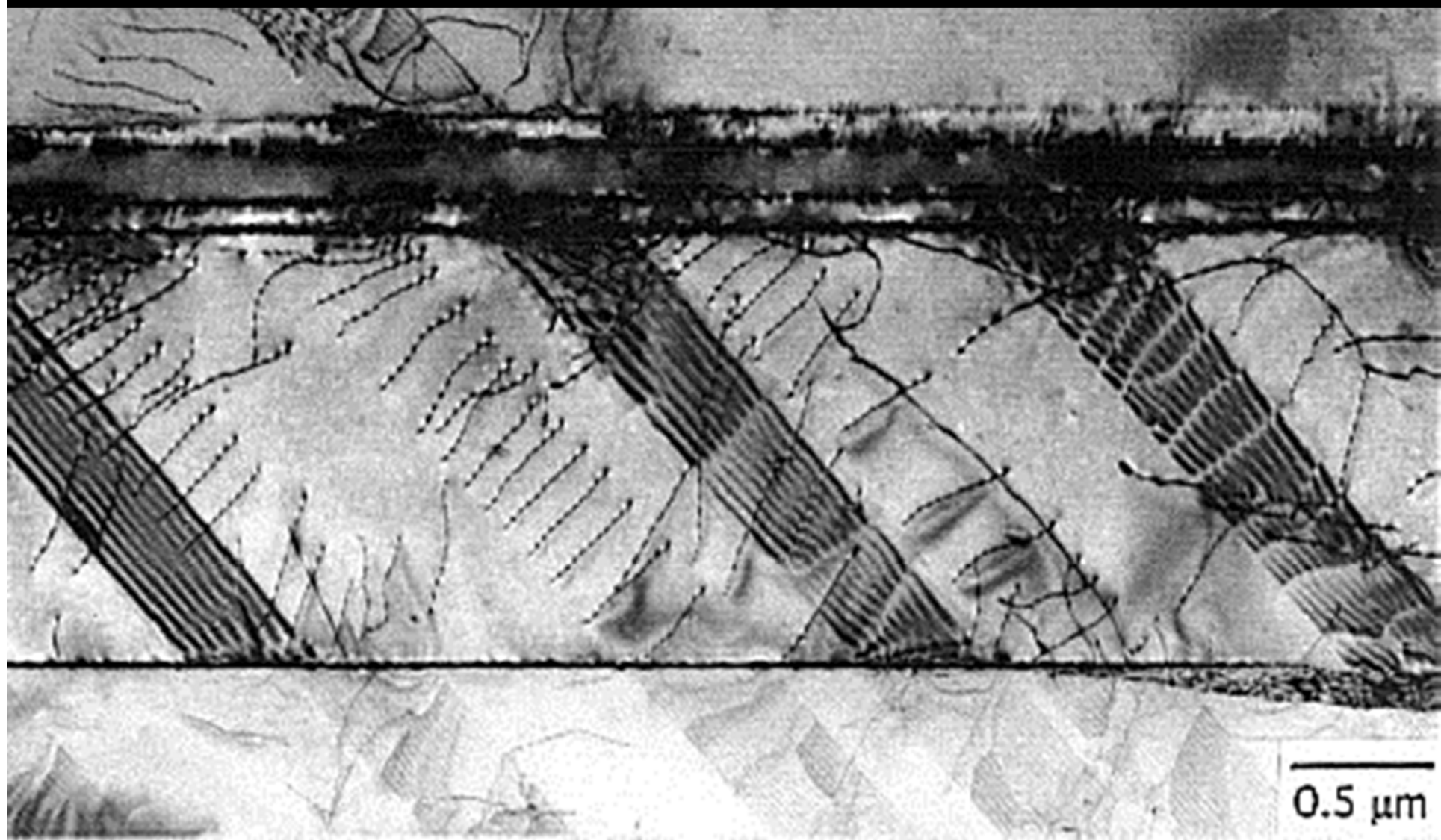


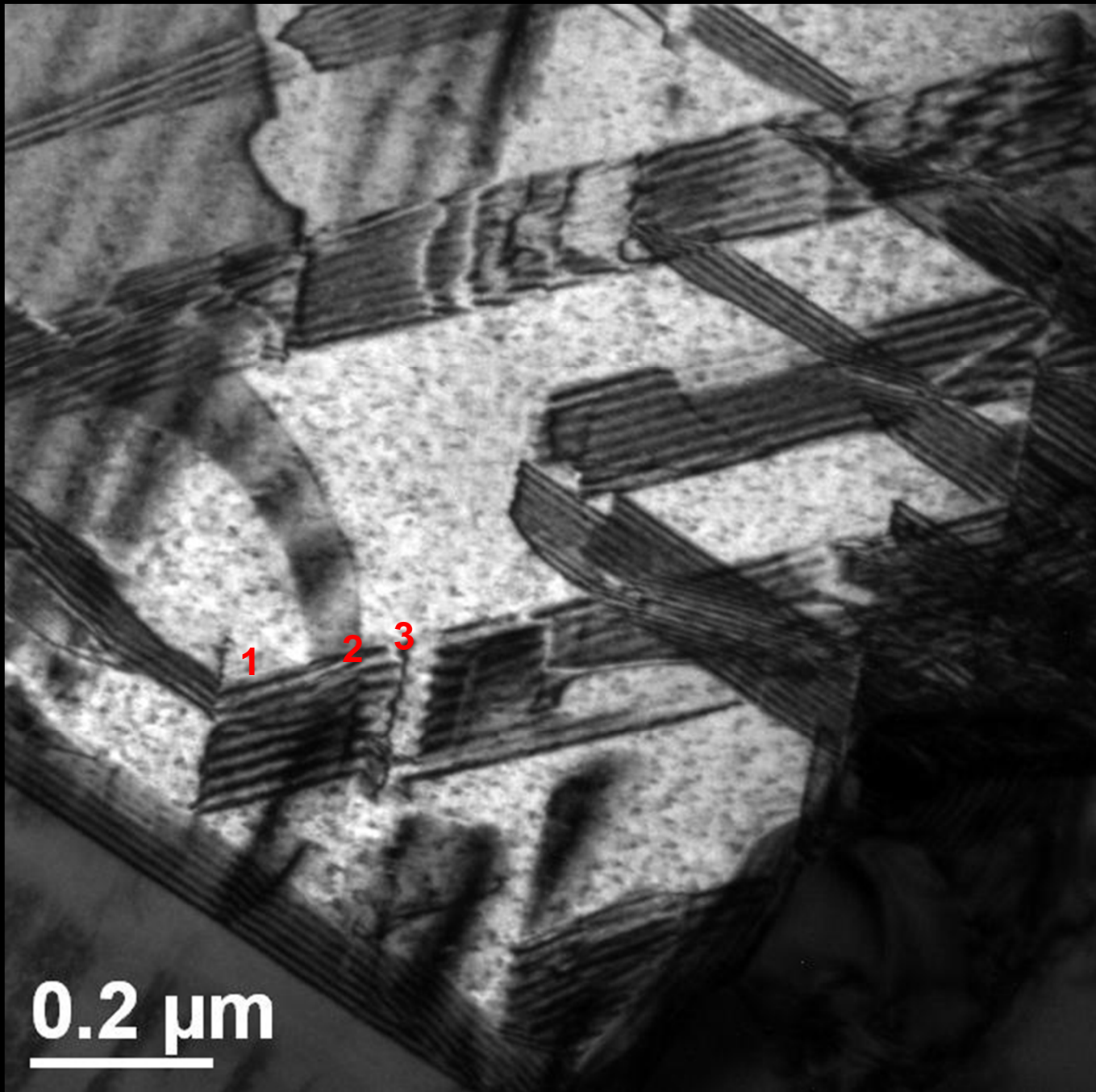


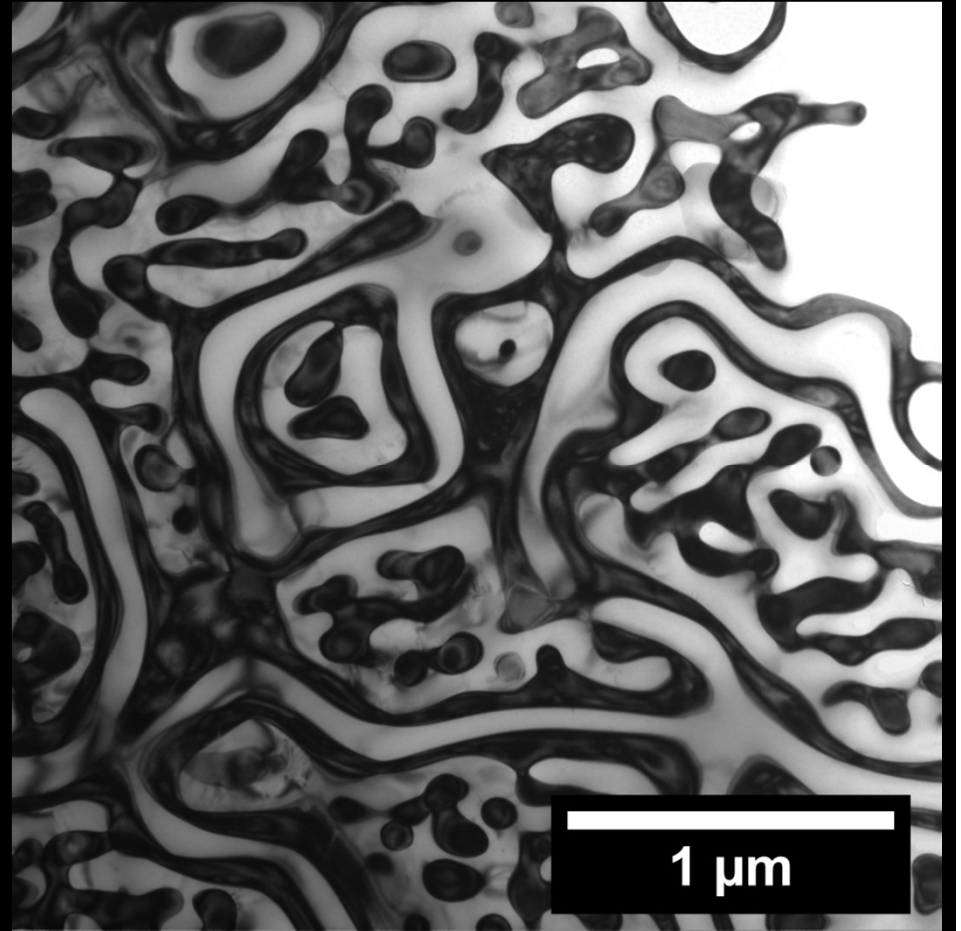
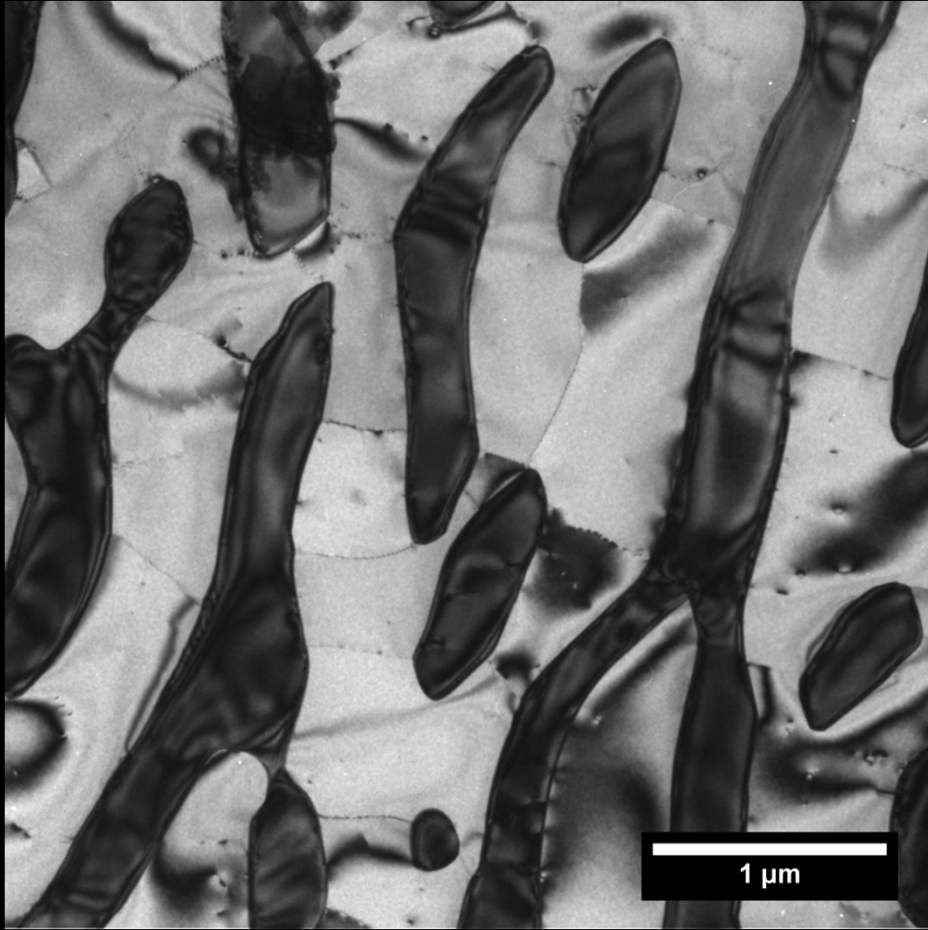




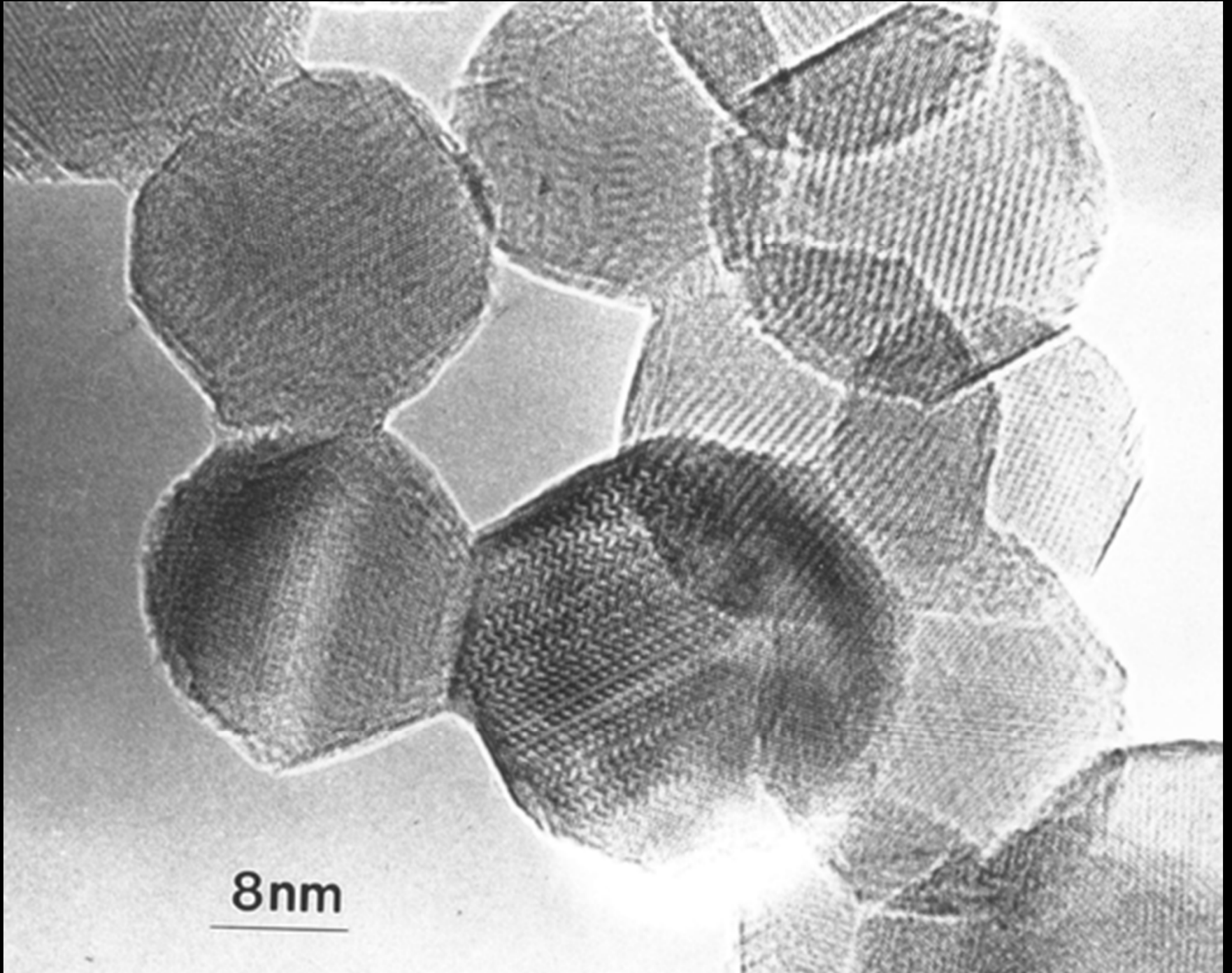




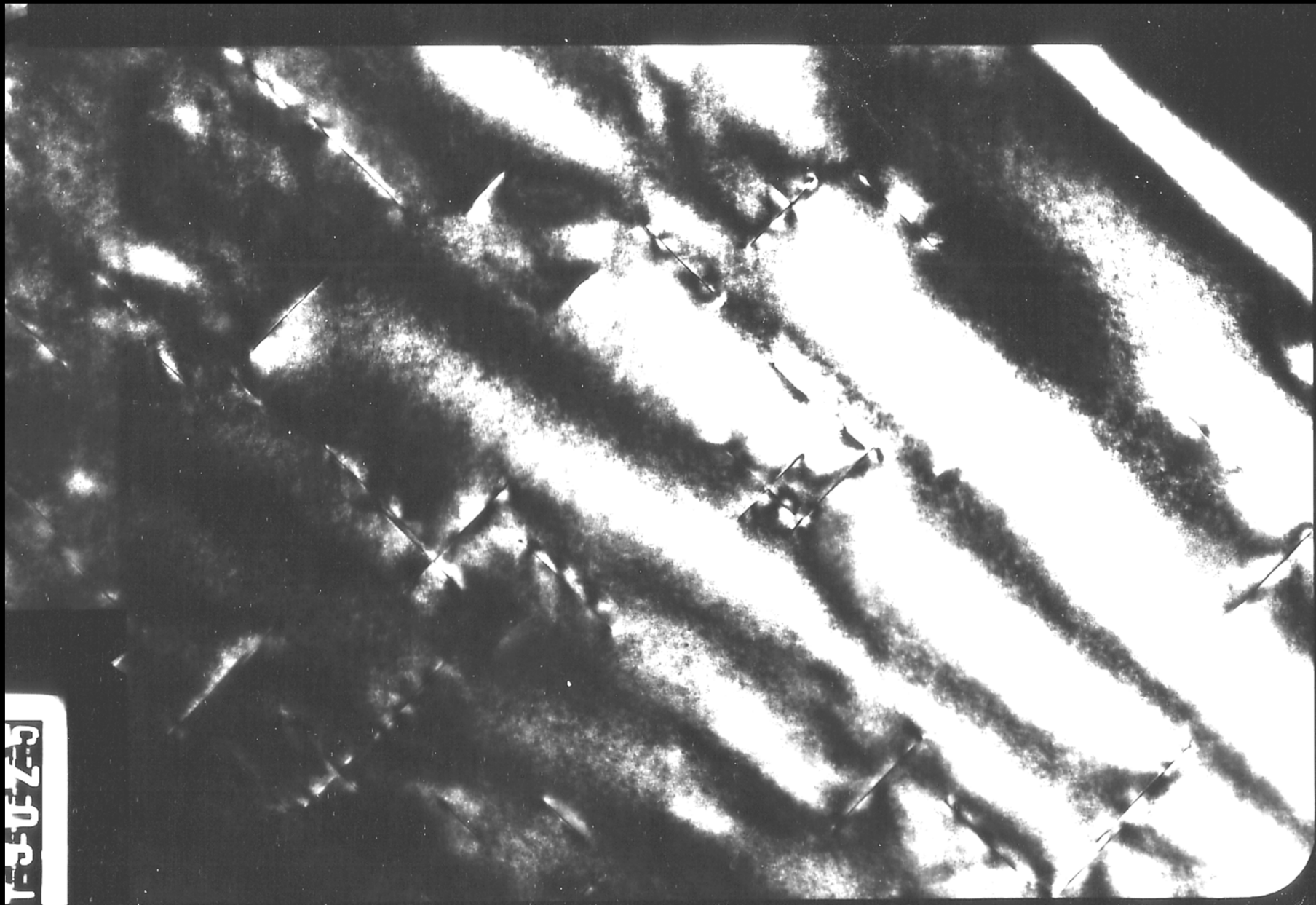




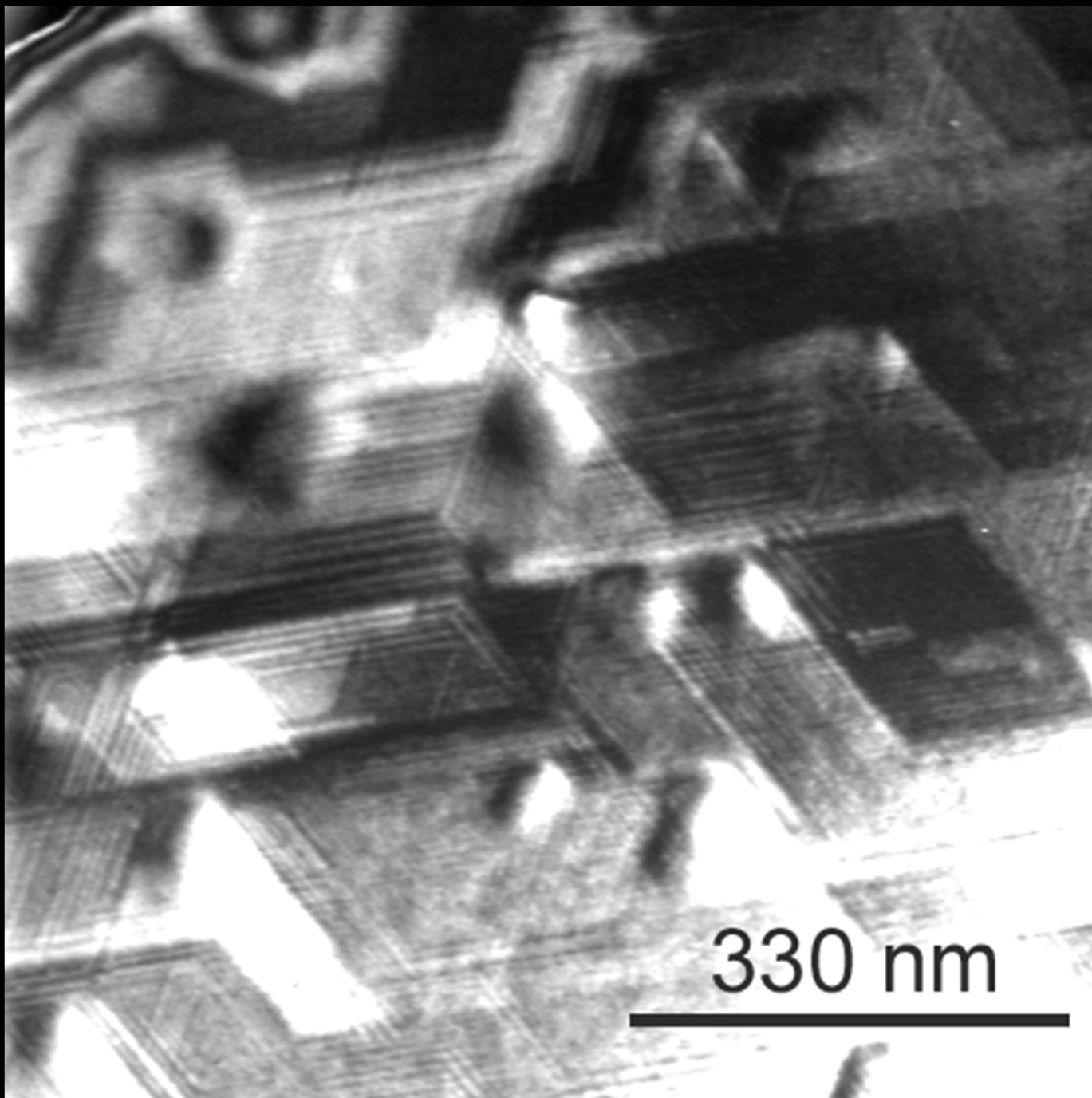




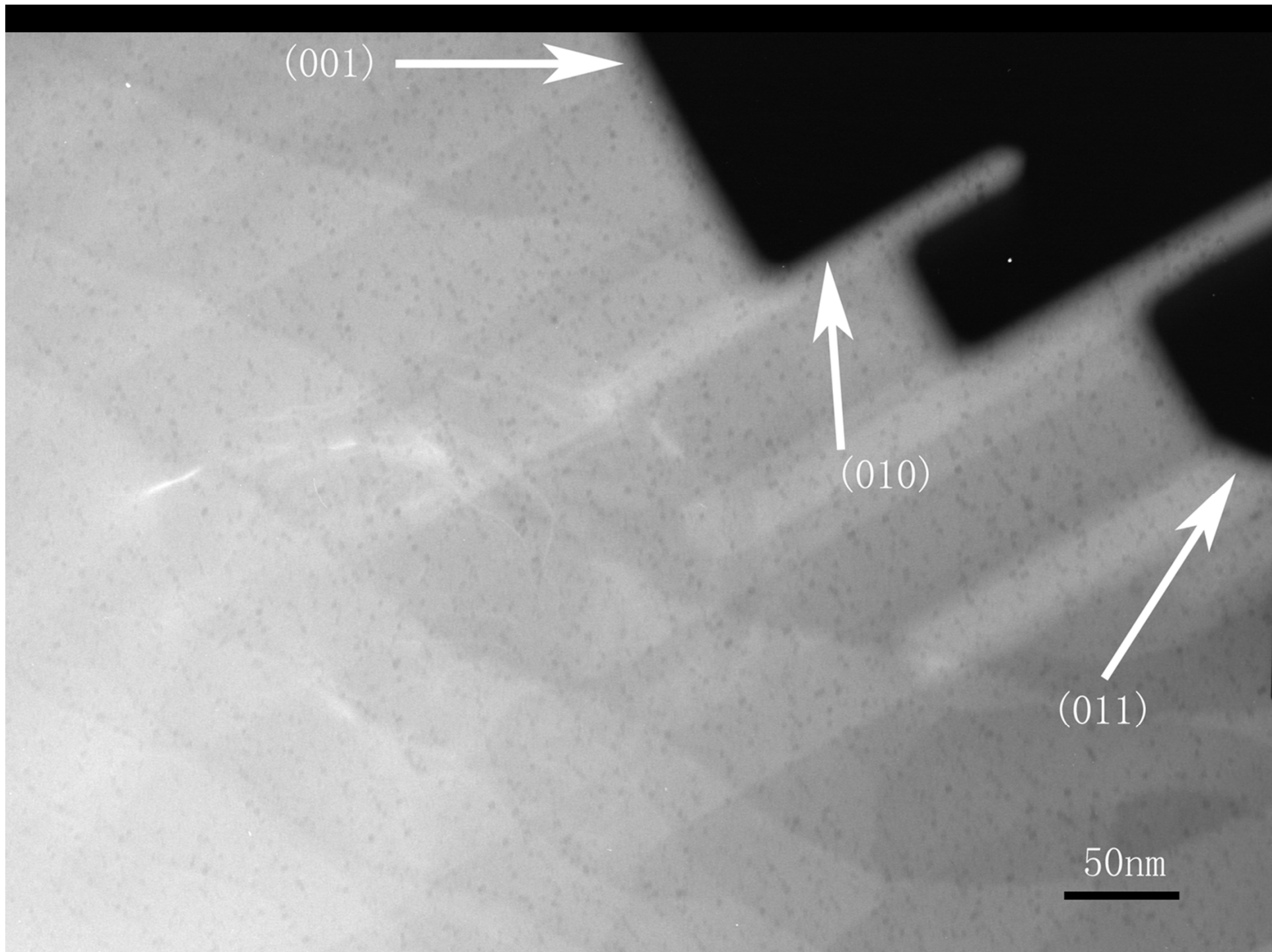
8nm

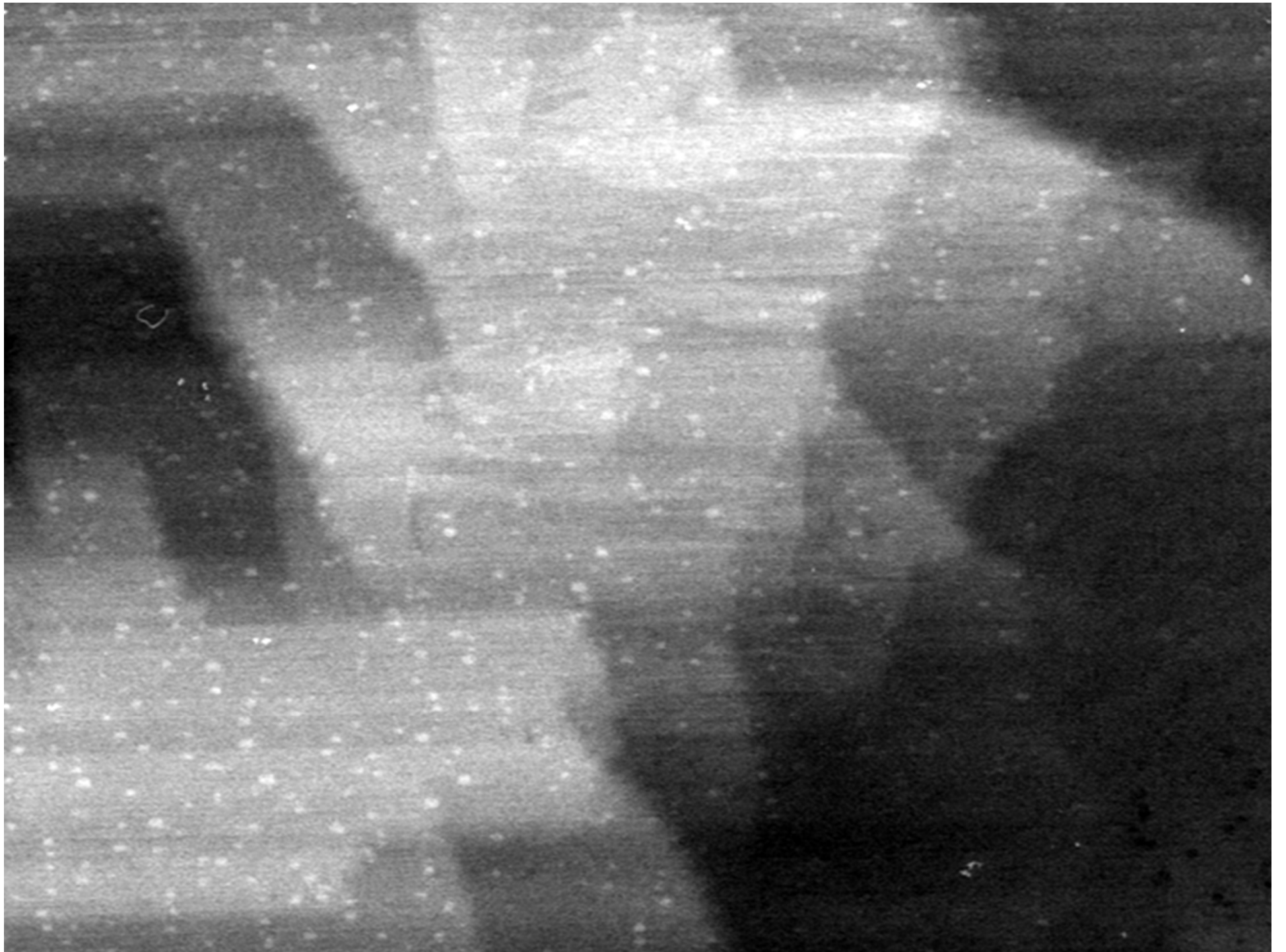


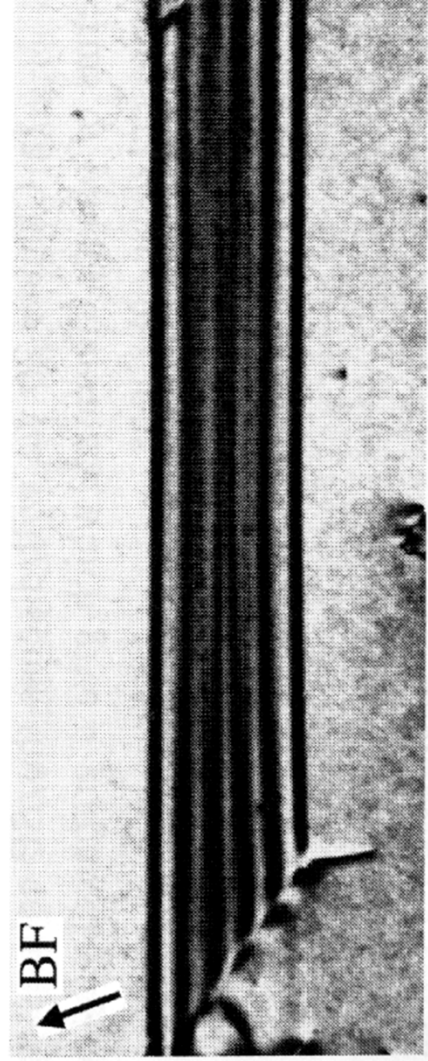
153-70-25



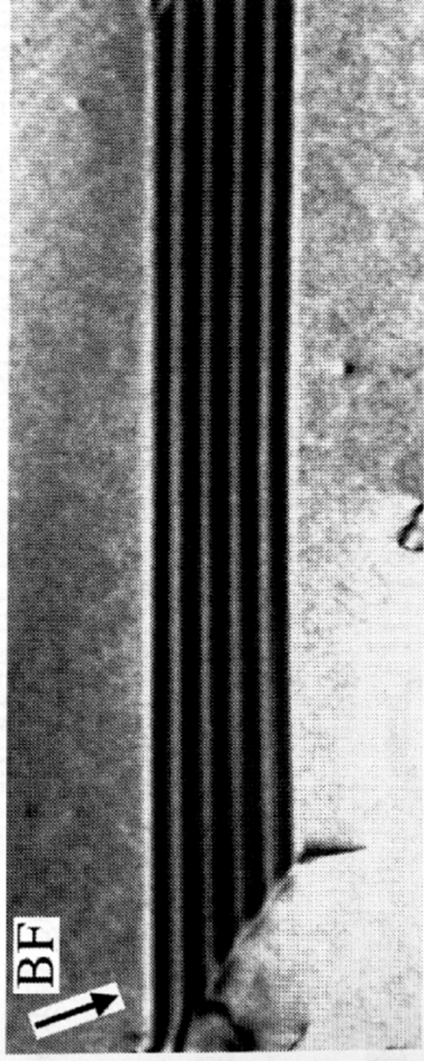
330 nm



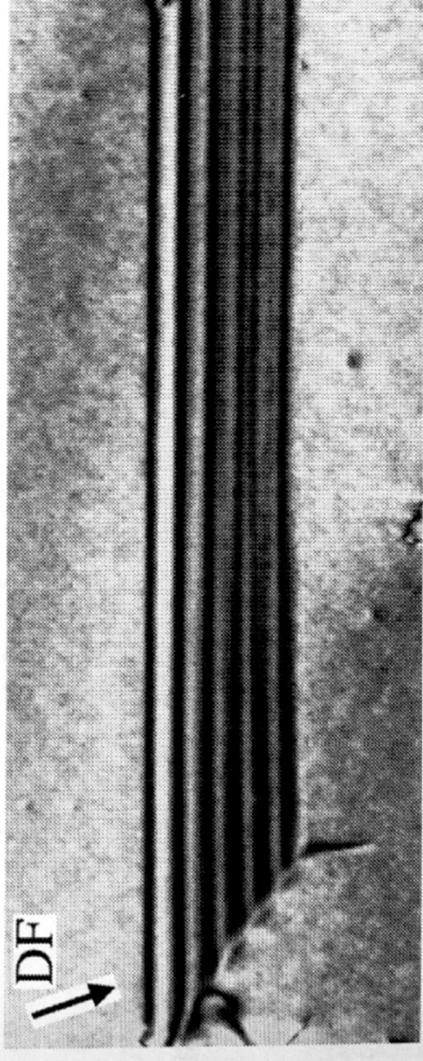




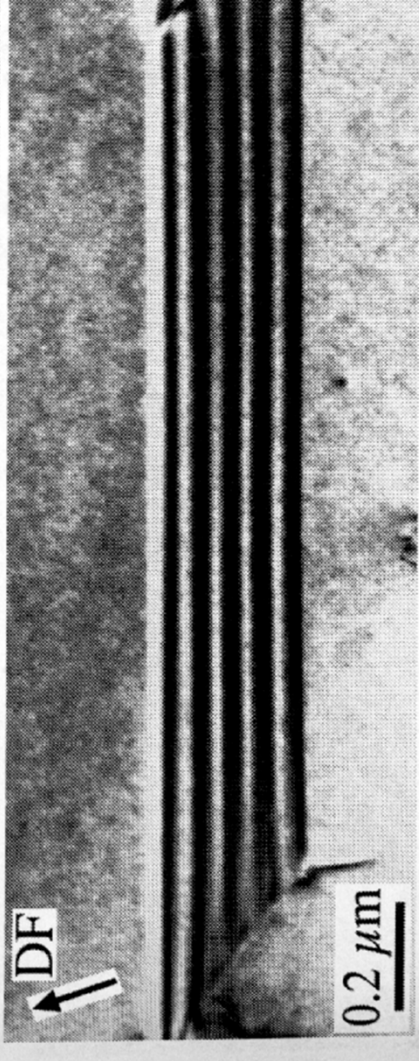
A



B

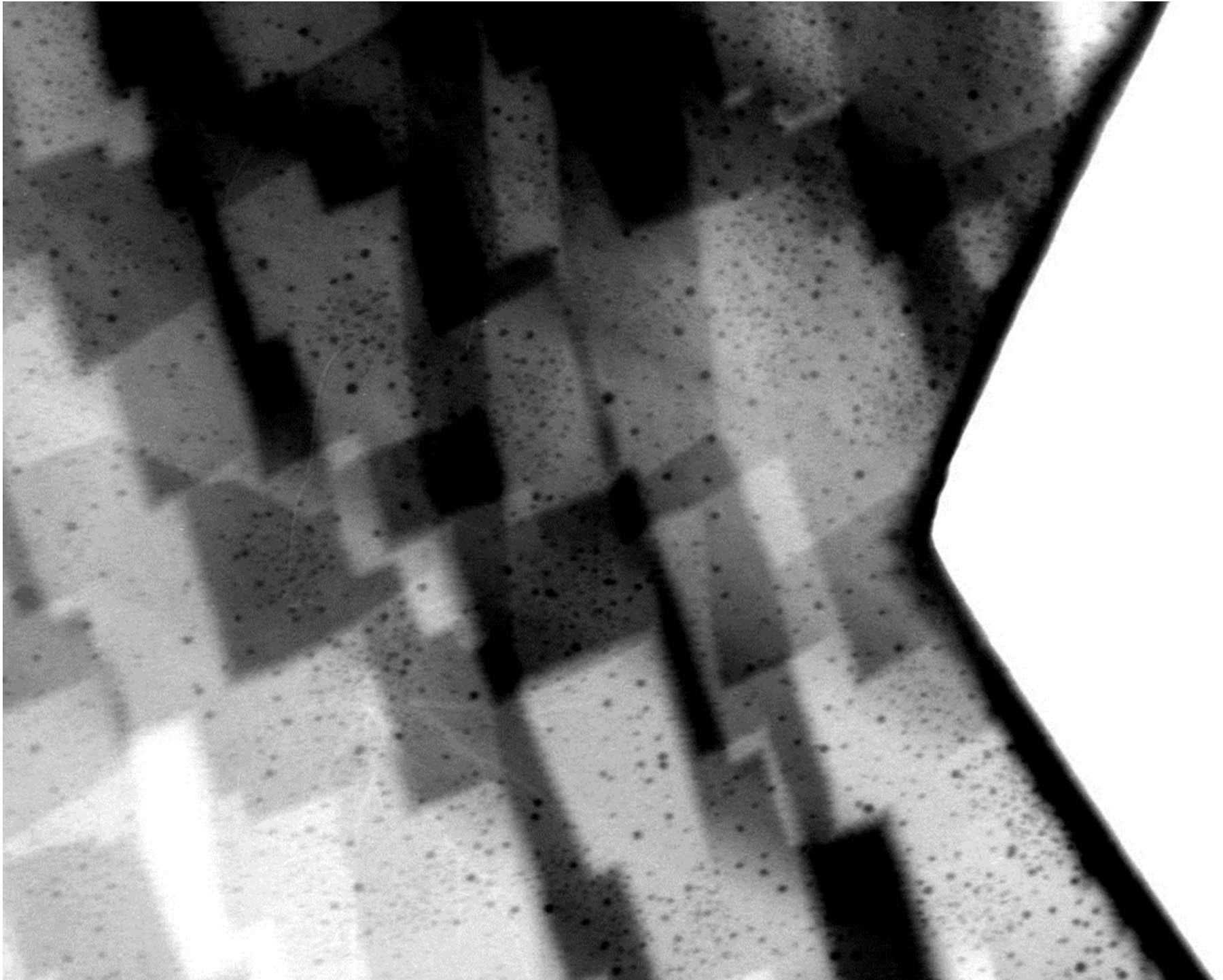


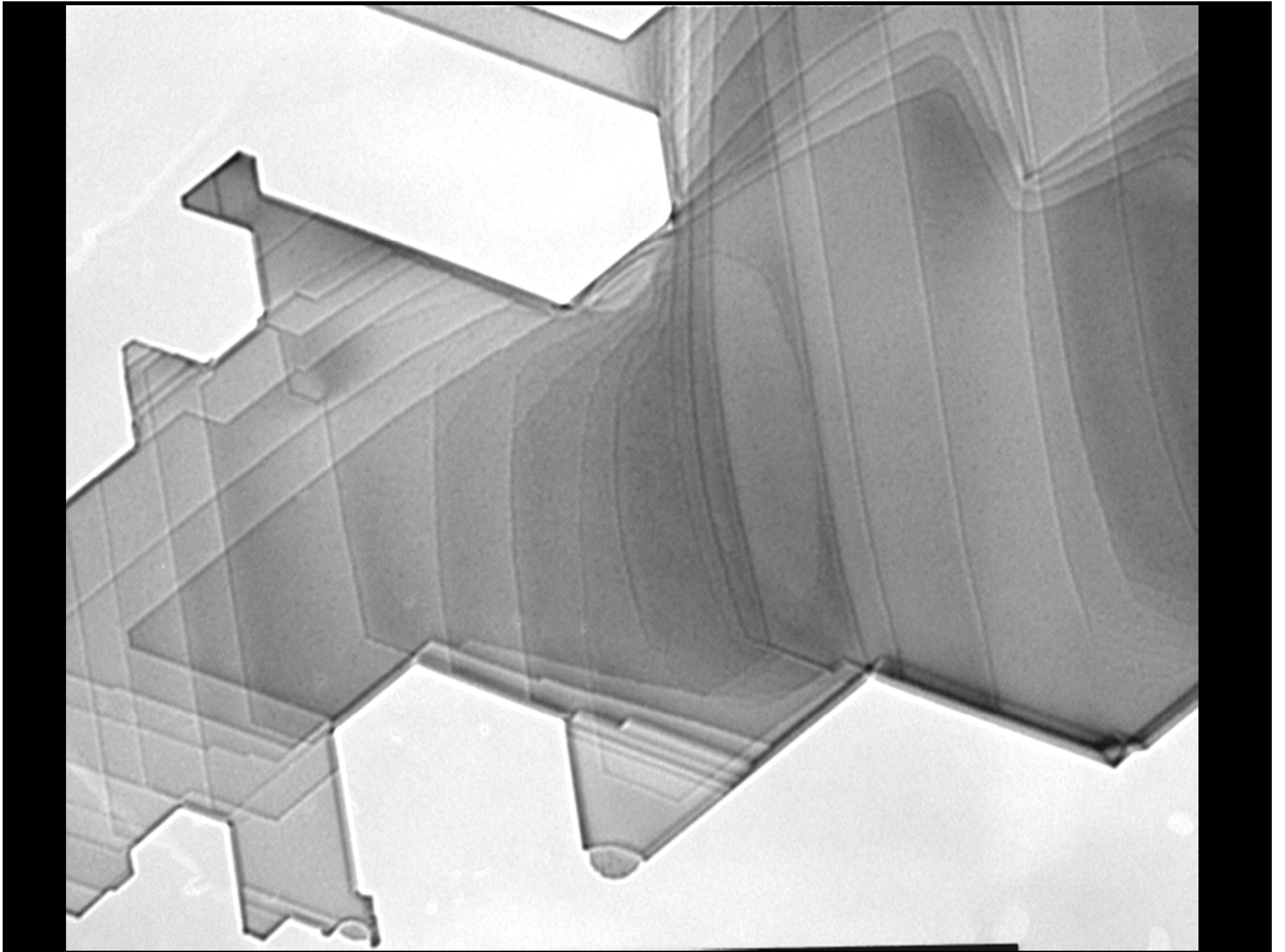
C

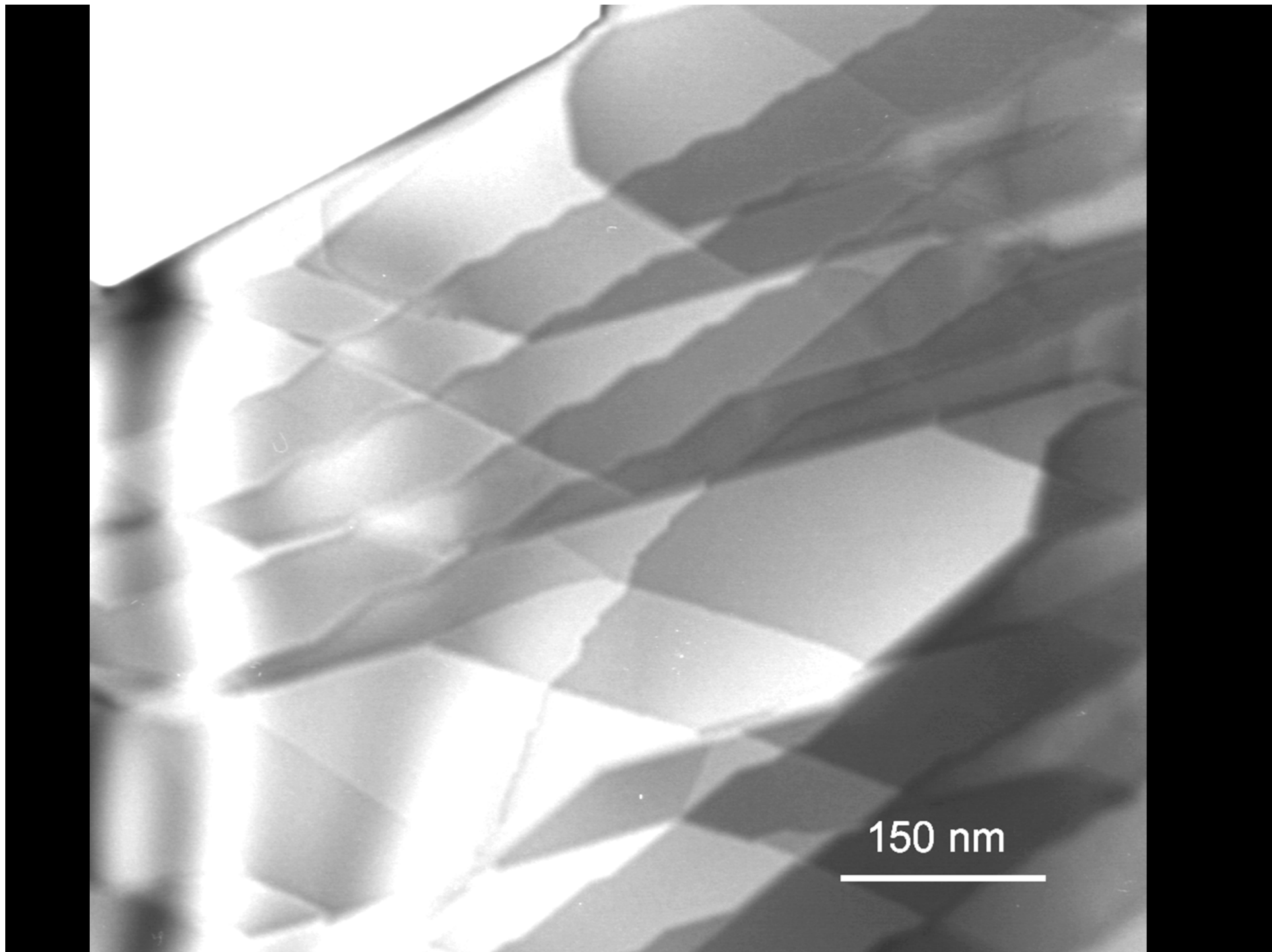


D

0.2 μm







150 nm